

# Did you miss a previous IMS ?



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**MTT-11**  
Microwave Measurements Committee

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**MTT-11 workshops at IMS(2014)**

**Efficient RF Design Using Practical Behavioral Models - Bridging the Gap Between Measurements and Simulations**

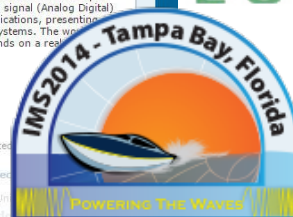
Presented at IMS 2014  
Topic: Circuit Characterization

**Organizers:**  
Marc Vanden Bossche, National Instruments  
Nuno Carvalho, Instituto de Telecomunicacoes

**Abstract:**  
Behavioral modeling is a topic that has been researched already extensively, surely in the power amplifier areas. Different techniques have been presented and discussed in the scientific world, like large-signal S-parameters, Volterra approaches, envelope domain etc. Meanwhile some trademark solutions are changing the way industry looks at behavioral models. But still there is a lot of confusion about the role and positioning of the different techniques. Recently these behavioral modeling tools moved also to other areas in the wireless community, such as energy harvesting and wireless power transfer devices, software defined radio, or in a more general sense mixed-signal devices. To realize a meaningful acceptance of behavioral modeling techniques, the models should be easy to use, easy to extract and should describe the behavior of the devices and systems in the best way possible, while being simple and intuitively. Presently behavioral modeling seems to be a tool for the happy few who can master the modeling theory, who understands the subtle measurements and who know how to use those models properly in a simulation environment. This is exactly where this workshop fits. The workshop brings together the modeling approaches, the instrumentation for parameter extraction and the simulation environments. It will position the different techniques against the application space, explain the capabilities and limitations. It will be possible to discuss these techniques and to have some hands on. The workshop will thus be divided into four different parts: Behavioral Model at the transistor level; in this part the important device characteristics are revised and it will be shown how behavioral models focus on these characteristics. Behavioral Model at the system level: other aspects of the behavior are important and in this part (sub-system models for Power Amplifier will be discussed including DPD approaches, and/or Mixed signal (Analog/Digital) Software Defined Radio enabled components. This will be complemented with behavioral model applications, presenting industrial use cases demonstrating how models did influence the design cycle of components and systems. The workshop will finish with a practical component, where some vendors will allow the attendance to put their hands on a real model test bench.

**Agenda:**

1. Large-Signal S-parameters: S-functions  
M. Vanden Bossche - National Instruments, Zaventem, Belgium
2. Measurement-based Nonlinear Behavioral Modeling of Transistors and Components  
D. E. Root, J. Xu, C. Gillespie, R. Biernacki, J. Verspecht - Agilent Technologies, Santa Rosa, United States  
T. Nielsen - Agilent Technologies, Aalborg, Denmark
3. Practical Wideband Time-Domain Measurement and Nonlinear System Level Modeling Techniques  
Traveling Wave Tube & Solid State Power Amplifiers  
C. R. Silva, C. J. Clark, A. A. Houtings, H. S. Mui - The Aerospace Corporation, Los Angeles, United States



Many previous MTT-11 sponsored workshops are available online at

[www.mtt11.org](http://www.mtt11.org)

# Large Signal Network Analyzer: Past and future of the LSNA

T. Reveyrand<sup>1</sup>, T. Inoue<sup>2</sup> and Z. Popović<sup>1</sup>

<sup>1</sup>University of Colorado at Boulder

<sup>2</sup>National Instruments

- Origins and history of the LSNA
- Commercially available NVNAs
- Applications
- Software approach
- Hardware approach
- Conclusion

1983

HP 8409



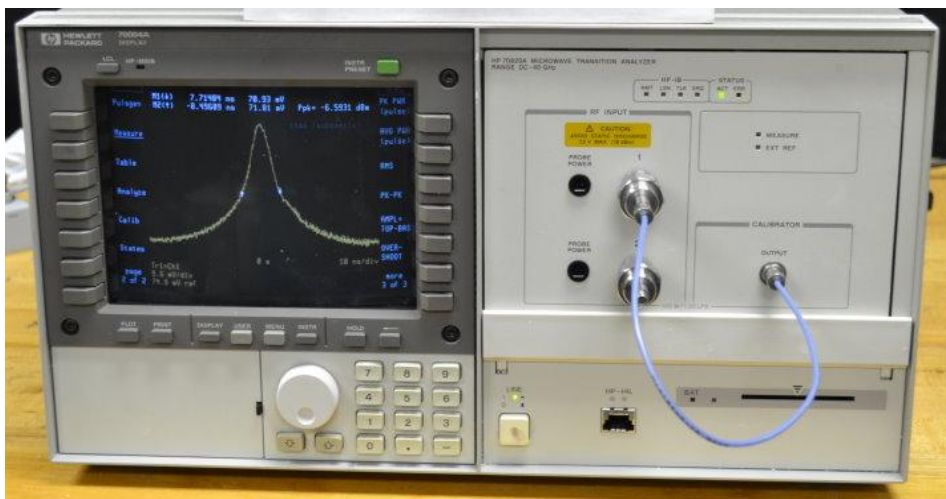
1985

HP 8510



HP 8510 in HP catalog from 1985 to 2001 (split with Agilent).





An HP 70820A microwave transition analyzer on an HP 70000 series mainframe.

500 Hz -40 GHz

**2 channels**

- Frequency and Power
- Vector voltage
- Network Analysis
- Power Sweeps
- Sampled Spectrum Analysis
- Array Processing

1991

HP 70xxx

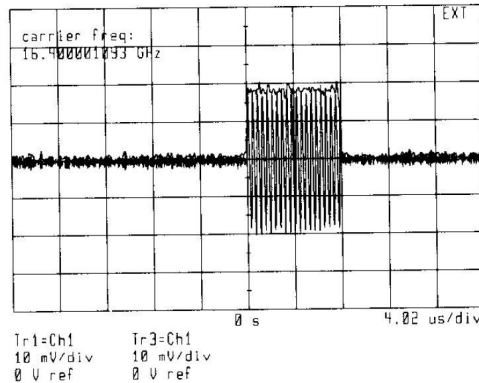
**The Microwave Transition Analyzer: A Versatile Measurement Set for Bench and Test (1991)**

HP Product Note 70820-1 [[Download](#)]



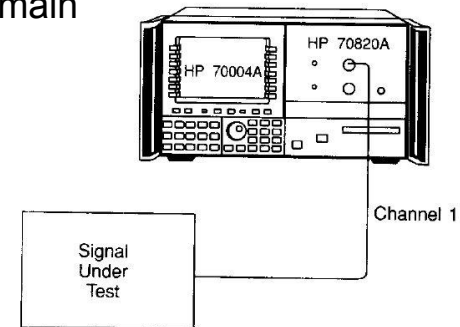
HP 70820A Microwave Transition Analyzer

## Pulsed RF measurements



*Pulsed RF shape  
directly display ( $>1\mu s$ )*

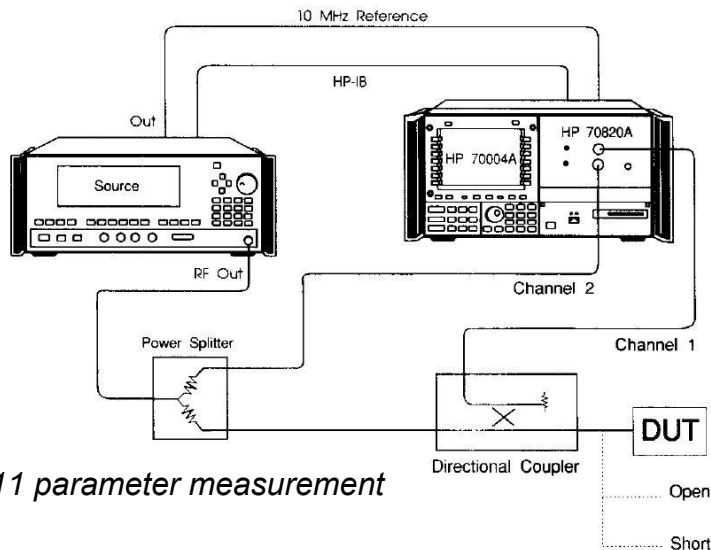
## Frequency Domain



```
source: CHAN1
300.000025 MHz -13.38 dBm 115.0 deg
2.30000006 GHz -16.65 dBm 162.7 deg
2.00000004 GHz -13.98 dBm 56.2 deg
1.69999992 GHz -37.13 dBm -73.0 deg
6.00000018 GHz -38.68 dBm 143.7 deg
```

*Up to five CW signals with their harmonics  
MAG and PHASE measurements*

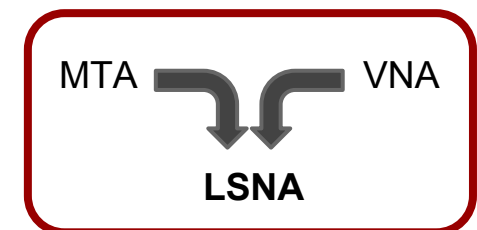
# Vectorial Analysis Domain



### S11 parameter measurement

10 MHz Bandwidth  
1024 points  
Frequency Calibrated

Compression point = 0 dBm  
Noise floor = -75 dBm  
Harmonic Distortion < -65 dB



## Example

from HP Product Note 70820-1

$$f_{RF} = 1 \text{ GHz}$$

$$f_{IF} = 100 \text{ kHz}$$

$$f_{IF} = f_{RF} - N \cdot f_{Fs}$$

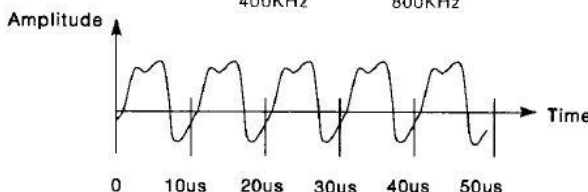
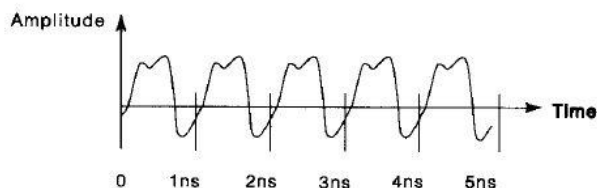
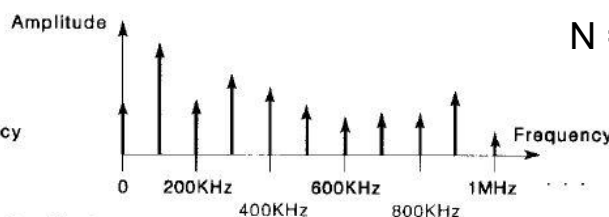
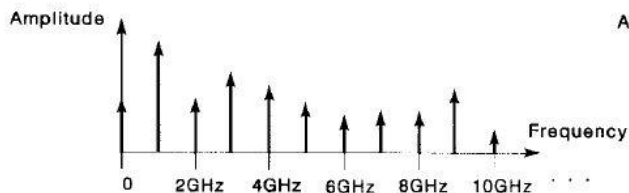
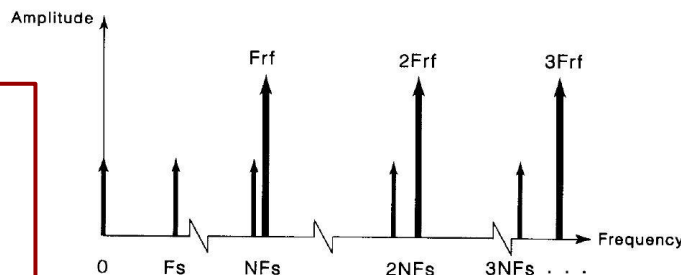
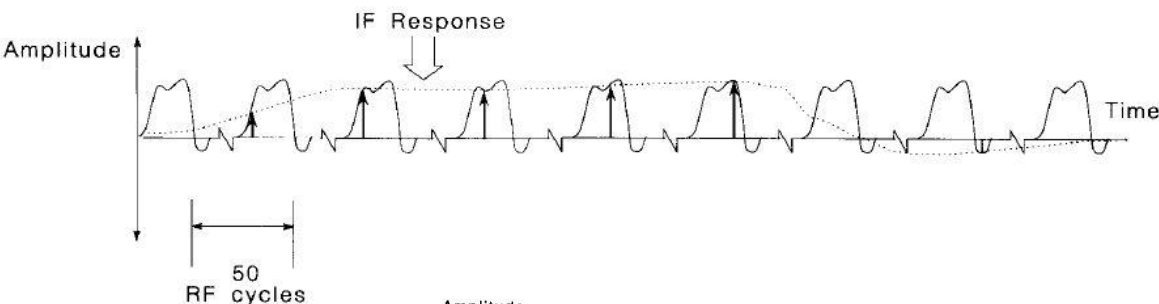
$$N = 49 \Rightarrow f_{Fs} = 20\,406\,122 \text{ Hz}$$

$$N = 50 \Rightarrow f_{Fs} = 19\,998\,000 \text{ Hz}$$

$$N = 51 \Rightarrow f_{Fs} = 19\,605\,882 \text{ Hz}$$

$$N = 52 \Rightarrow f_{Fs} = 19\,228\,846 \text{ Hz}$$

Sub-sampling  
=  
Mixing with  
a comb generator



a. RF signal

b. IF signal

Frequency allocation in :

- A LSNA ;
- An Harmonic Balance Simulation

# MTA's block diagram

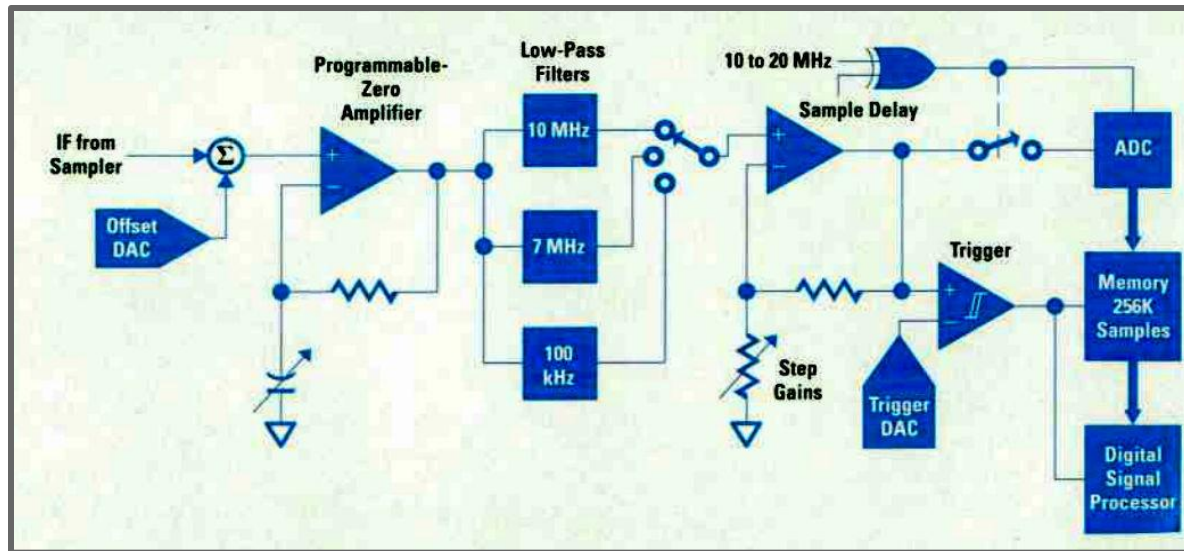
Origins

NVNAs

Applications

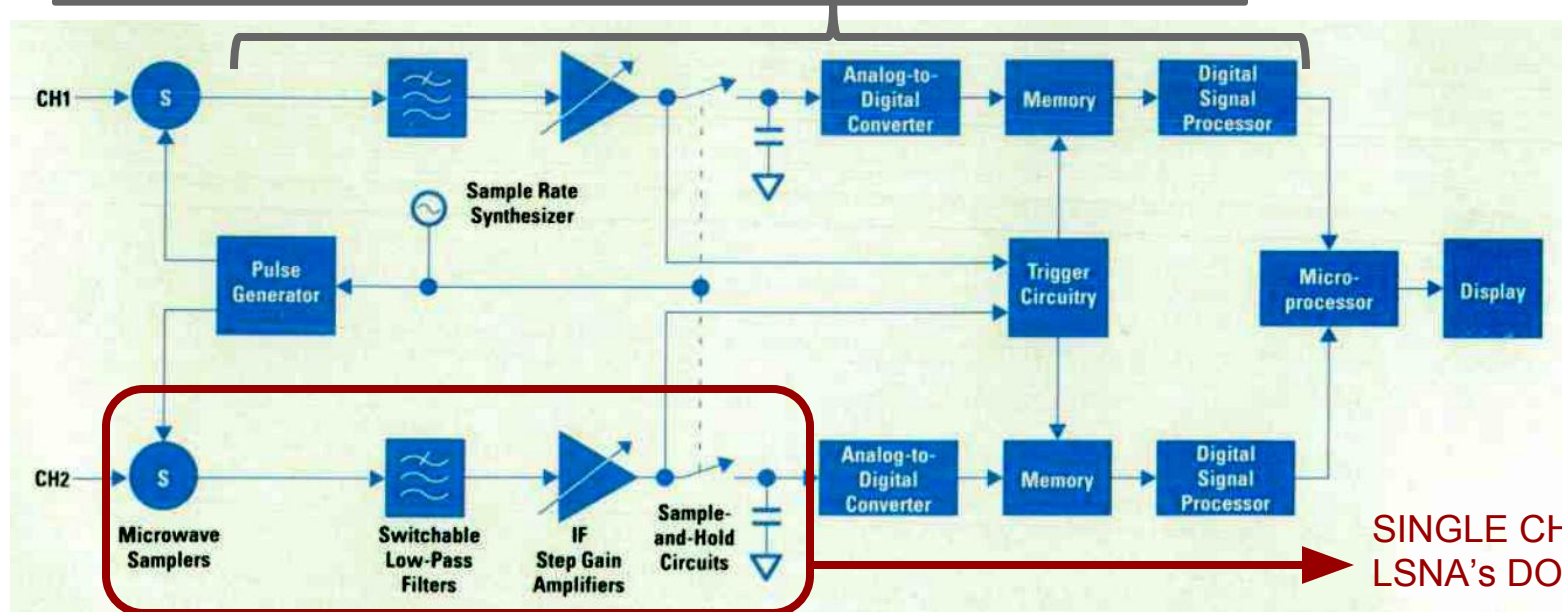
Software

Hardware



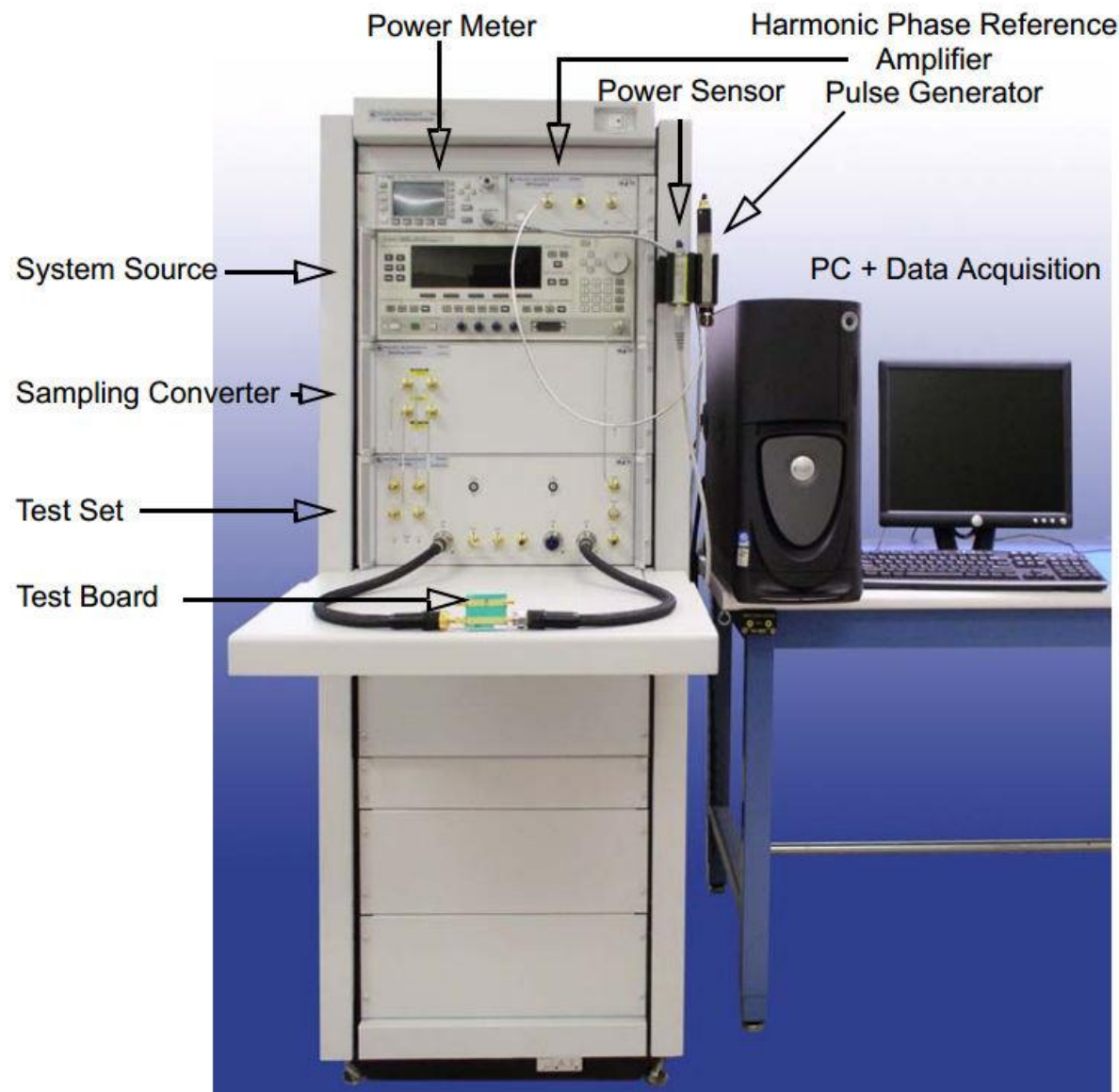
Pictures from  
"Hewlett Packard Journal",  
October 1992  
[\[Download\]](#)

**A MTA is basically a sparse  
frequency domain SCOPE**



**SINGLE CHANNEL  
LSNA's DOWNCONVERTER**





## 2000's

Commercial LSNA system

*Started in 1994 by HP-NMDG  
under the name NNMS*

*4 channels receivers*

+

*2 bi-directional couplers*

ADC evolution from  
VXI (Agilent version) to  
PCI (Maury version)

But the sampling converter is  
based on discontinued MTA  
receivers.

Subsampling frequency:

**16-20 MHz**

RF bandwidth:

**50 GHz**

Picture from MT4463 Data Sheet [\[Download\]](#)





VTD (founded in 2008) was a spin-off from  
Jan Verspecht bvba (Belgium) and  
XLIM labs (Limoges University, France)

## 2008-2012

The last LSNA

**LSNA redesigned from scratch**

Sampling converters board  
(including pulse shaping)  
originally developed by Anapico  
<http://www.anapico.com/>

Subsampling frequency:

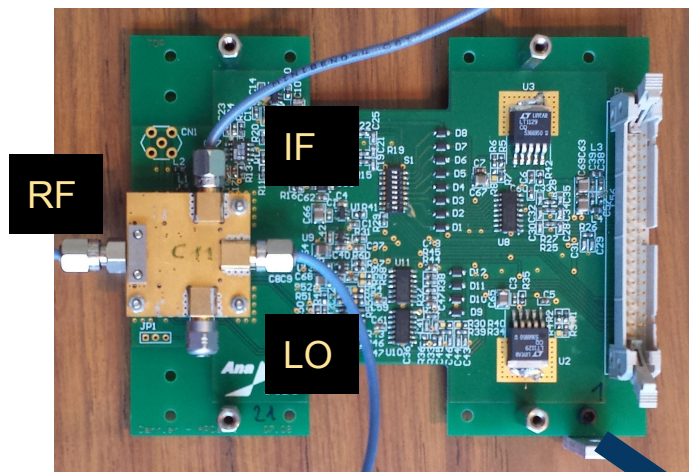
**600-1200 MHz**

RF bandwidth:

**30 GHz**



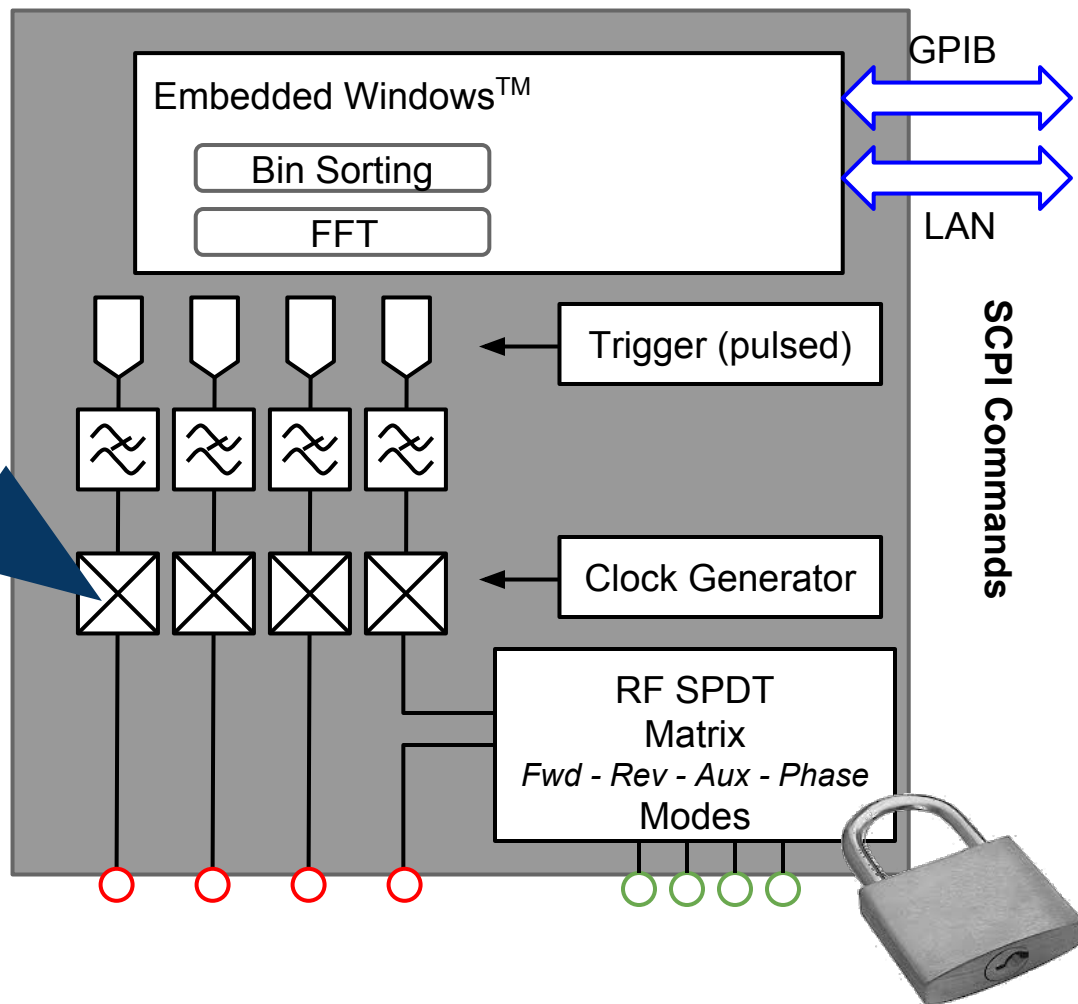
VTD has been acquired by Agilent Technologies Inc. on June 2012



One of the four sub-samplers

- All-in-one downconverter box including the RF switch matrix
- External bi-directional couplers
- Smart SCPI commands to get only important data
- No GUI

**A LSNA receiver is a sparse frequency domain analyzer but NOT a SCOPE**





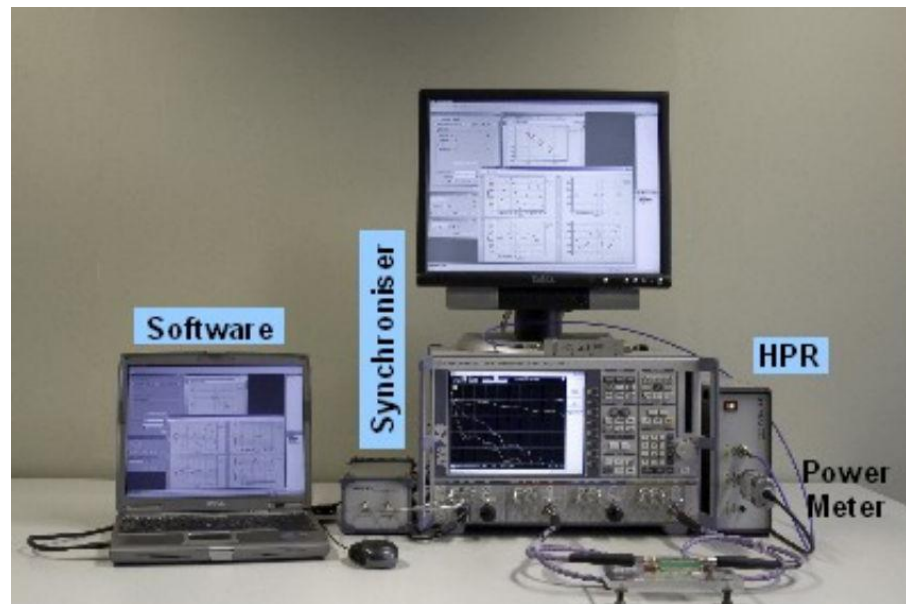
*The LSNA is dead, long live The NVNA!*

**NO WAY!**

**WHY?**



**Agilent PNA-X**  
(with Non-Linear option)



**Rohde & Schwarz ZVA**  
(ZVxPlus option powered by NMDG)

Single shot subsampling acquisition = sequential mixer-based acquisitions

**D. Barataud et al.**

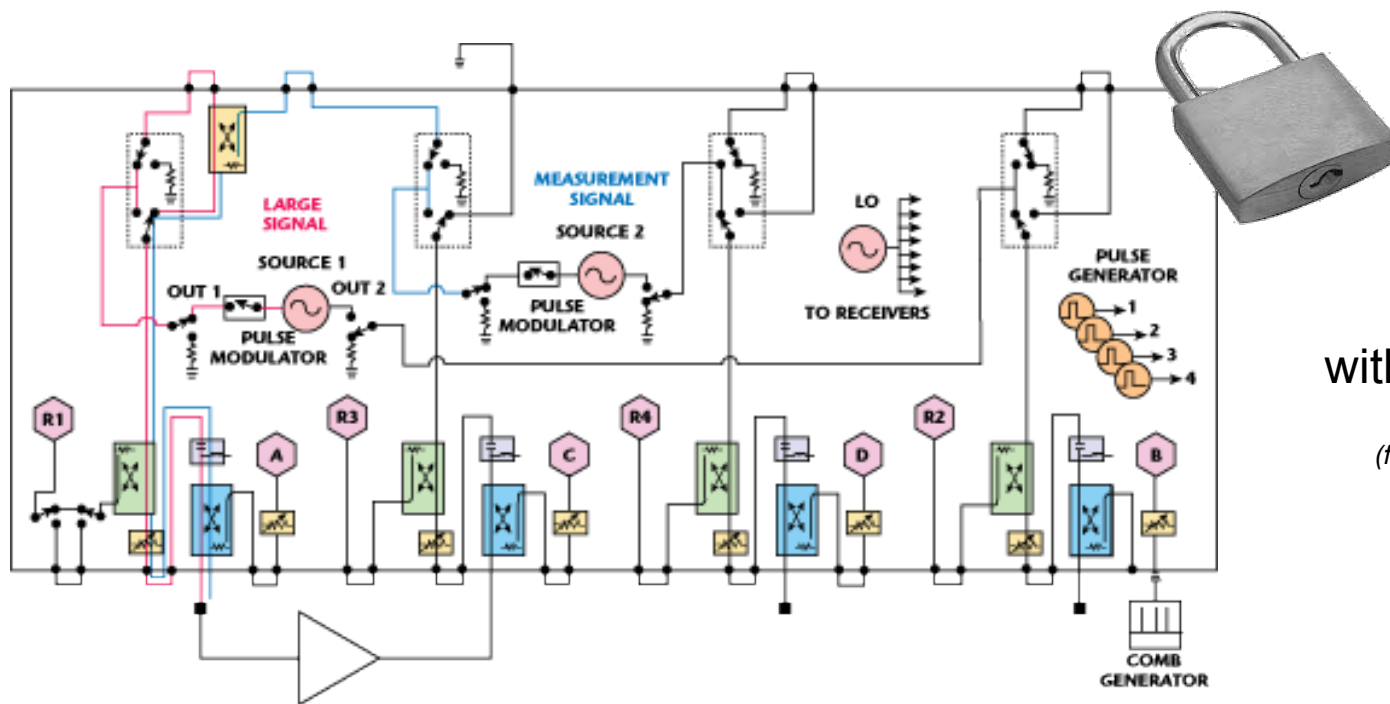
*"Measurements of time-domain voltage/current waveforms at RF and microwave frequencies based on the use of a vector network analyzer for the characterization of nonlinear devices-application to high-efficiency power"*

IEEE Trans. on Instrumentation and Measurement,  
Vol. 47, no 5, pp 1259-1264, 1998

[\[Link\]](#)

- 4-ports VNA in receiver mode ;
- 2 comb generators

**EXTENSIVE HARDWARE**



Agilent PNA-X  
with Non-linear Option

(figure from [Microwave Journal](#))

## OK, BUT WHY DO I NEED A NVNA/LSNA?

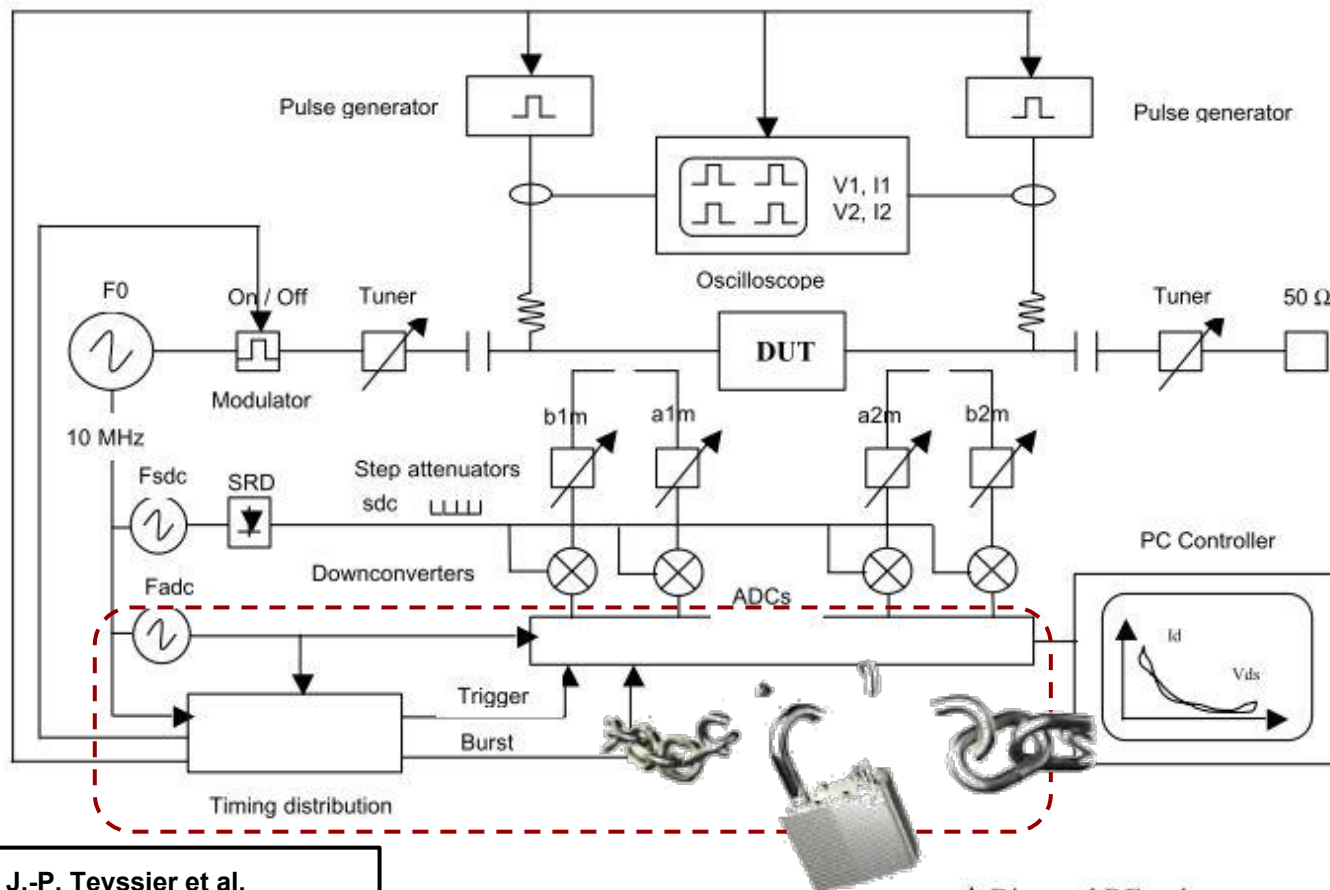


## Instrumentation Improvement

- Pulsed RF measurements (Hardware)
- Pulsed RF measurements (Software)

## Improve PA efficiency

- Class-F Validation of a MMIC PA
- Harmonic Injection PA Design
- Outphasing Experiments
- Envelope Tracking Analysis...



Example:

$F_0 = 1 \text{ GHz}$

$F_{sdc} = 19.6 \text{ MHz}$

$F_i = 400 \text{ kHz}$

$F_{adc} = 12.8 \text{ MHz}$

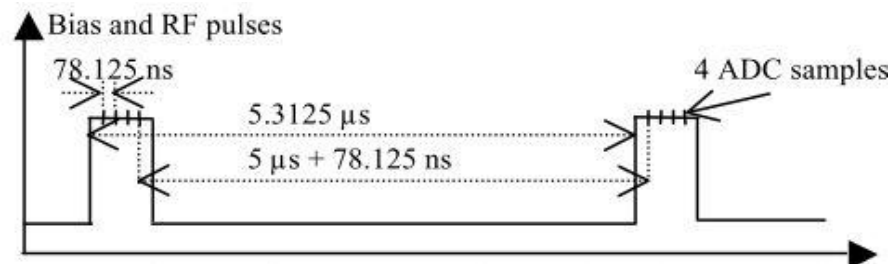
Samples = 2048

FFTbin = k.64

ADC Acquisition:  
512 burst of 4 samples

J.-P. Teyssier et al.  
"Large-Signal Time Domain  
Characterization of  
Microwave Transistors under  
RF Pulsed Conditions"  
57th ARFTG Conference  
(Spring), 2001  
[\[Link\]](#)

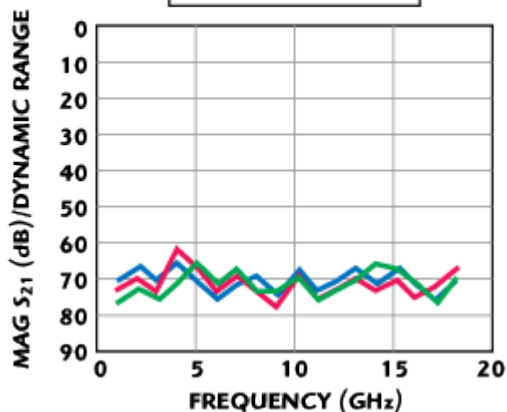
**CALIBRATION  
IN  
CW**



## Hardware embedded in SWAP X-402



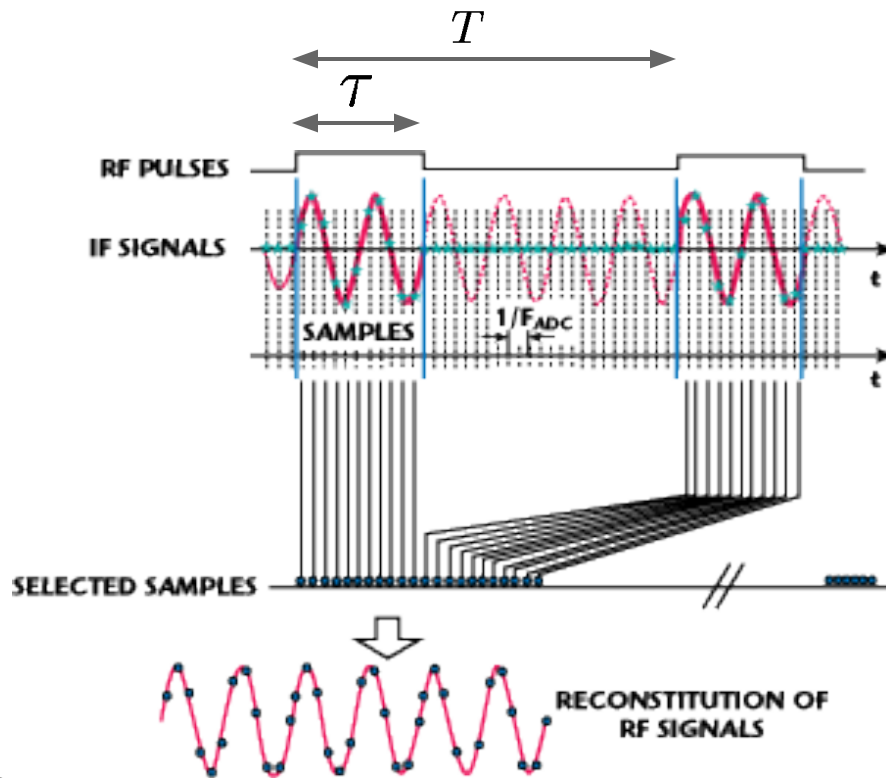
DUTY CYCLE (0.2%)  
DUTY CYCLE (1%)  
CW



**Result:**  
Dynamic Range  
not correlated with  
Duty cycle

**VNA Dynamic loss**

$$20 \cdot \log_{10} \left( \frac{T}{\tau} \right)$$



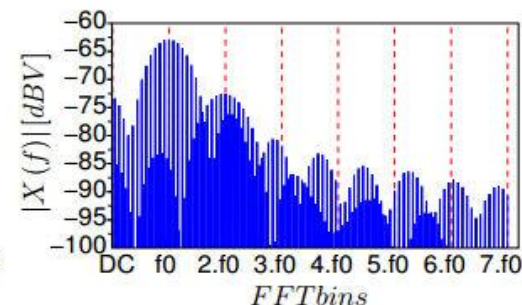
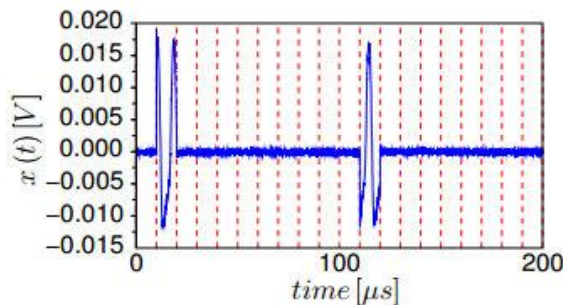
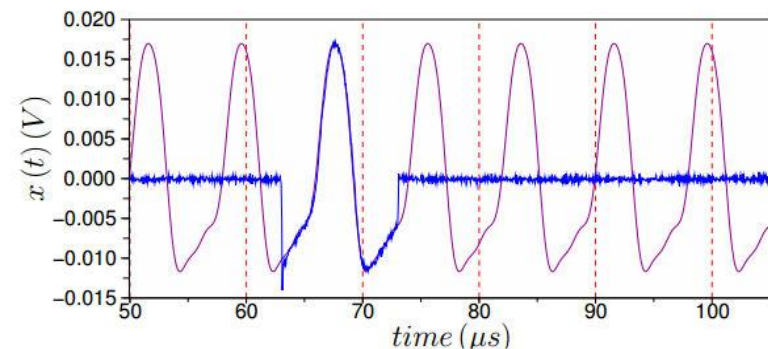
**J. Faraj et al.**

“A Repetitive Sampling Receiver for Pulsed Time Domain Load-Pull”,  
Microwave Journal, September, 2011  
[\[Link\]](#)

**TABLE I**

ACQUISITION MEASUREMENTS TIME FOR DIFFERENT DUTY CYCLES

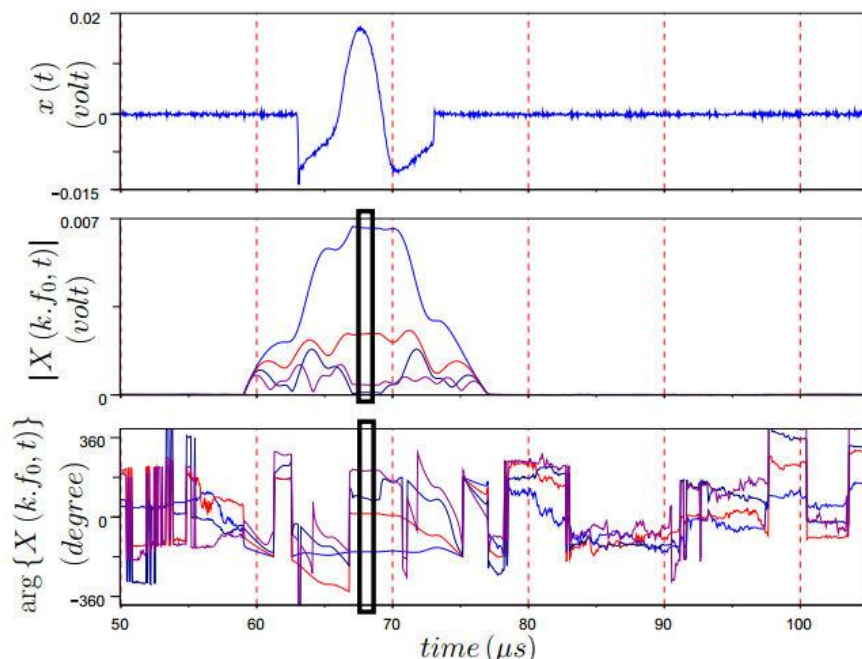
Duty Cycle (%)	(1/10)100	(1/100)100	(1/1000)100
Acquisition Measurement Time	10 $\mu$ s	100 $\mu$ s	1000 $\mu$ s



## CALIBRATION IN CW

FFT after  
ADC acquisition

Replace FFT with STFT  
(Short Time Fourier Transform)

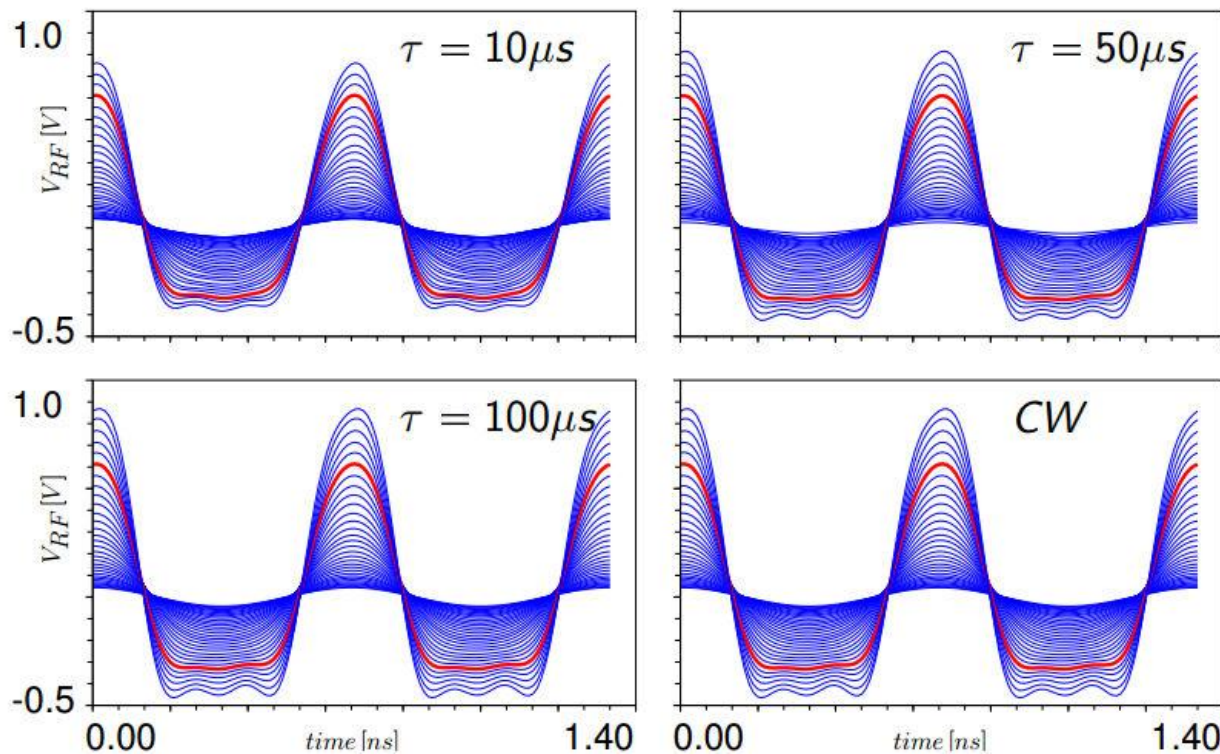




$$f_{RF} = 1.5\text{GHz}$$

$$T_{\psi} = 8\mu\text{s}$$

$$k \in \{1, 2, 3, 4\}$$



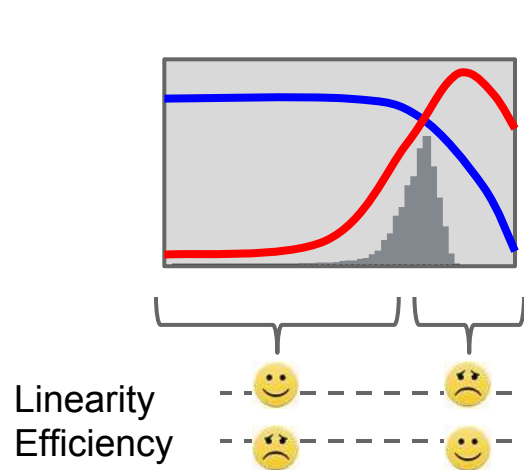
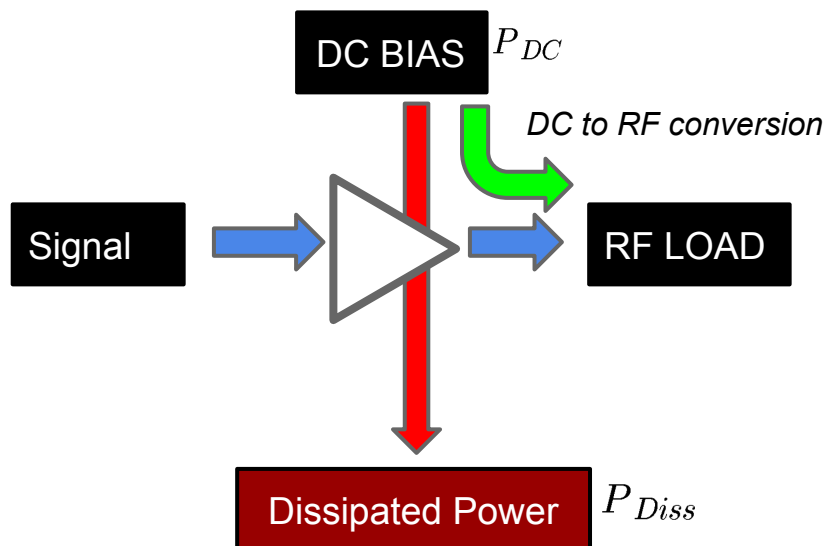
**T. Reveyrand, Z. Popović**

“A new method to measure pulsed RF time domain waveforms with a sub-sampling system”  
IEEE IMS 2012.

[\[Download\]](#)

- Compatible with CW and pulsed signals
- Adaptive method
- No trigger
- Pulse's width and period (  $\tau$ ,  $T$  ) not required

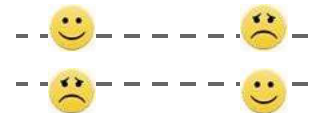


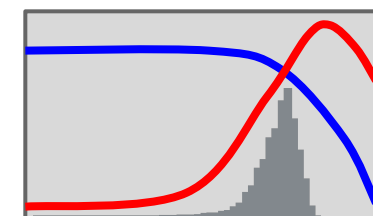
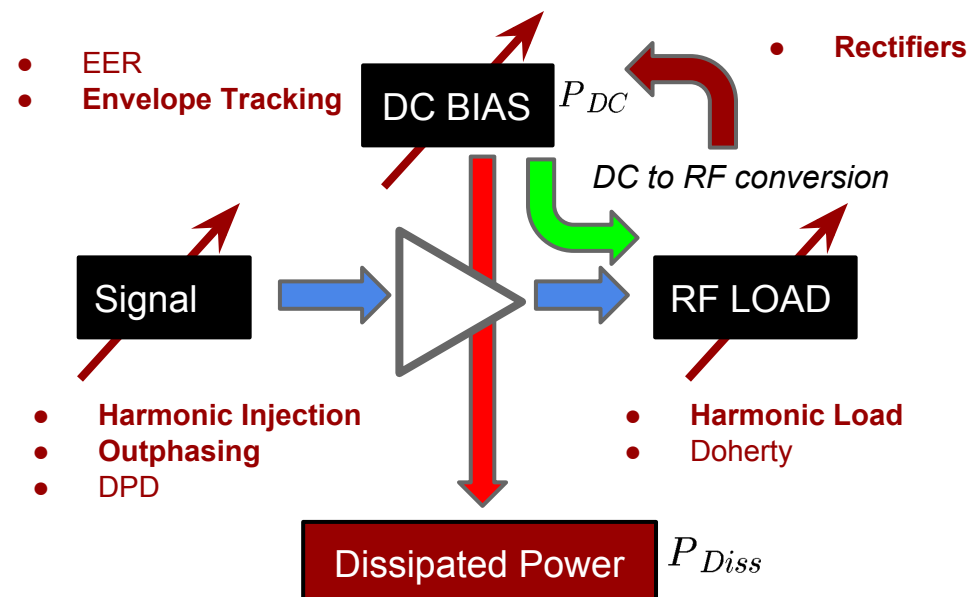


$$PAE(\%) = \frac{P_{Diss}}{P_{DC}}$$

Power Gain  
Efficiency (PAE)

Linearity  
Efficiency

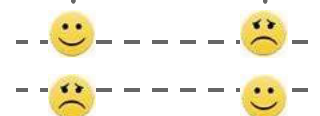




$$PAE(\%) = \frac{P_{Diss}}{P_{DC}}$$

Power Gain  
Efficiency (PAE)

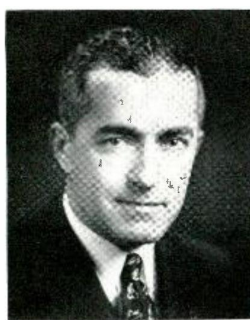
Linearity  
Efficiency



**BACK** ←  
TO  
THE **30's**



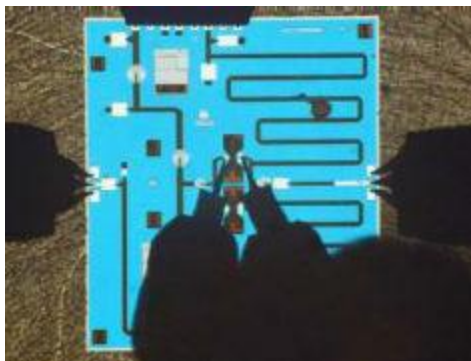
H. Chireix



W. H. Doherty

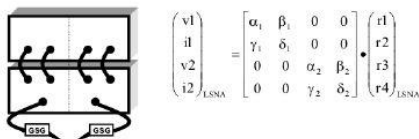
## LSNA's Applications

- Class-F Power Amplifier
- Harmonic Injection
- Outphasing
- Rectifiers
- Envelope Tracking



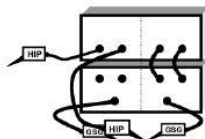
**T. Reveyrand et al.**  
 “Calibrated Measurements of Waveforms at Internal Nodes of MMICs with a LSNA and High Impedance Probes”  
 62nd ARFTG, Fall, 2003  
[\[Download\]](#)

## 1. NVNA calibration (LRRM)



→ Ref. plane = voltage standard

## 2. Calibration with 1 HIP



- HIP @ ref. plane
- « Sweep-sin »
- Measurements :  
 >  $V_2$  (NVNA calibrated)  
 >  $V_{HIP}$  (raw data)

$$\rightarrow \tilde{K}(f) = \frac{v_2(f)}{v_{HIP}(f)}$$

Method requires access to:

- Raw Data
- Calibration Measurements
- Error-terms

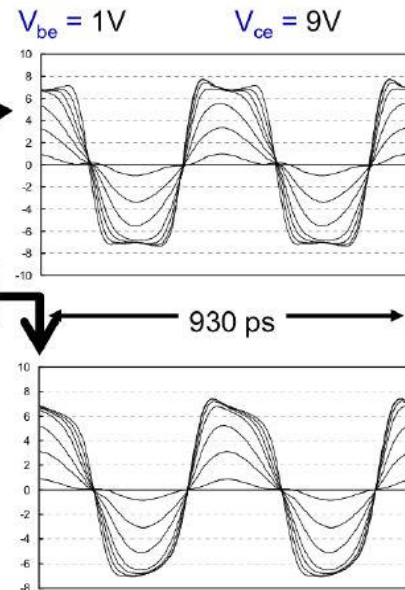
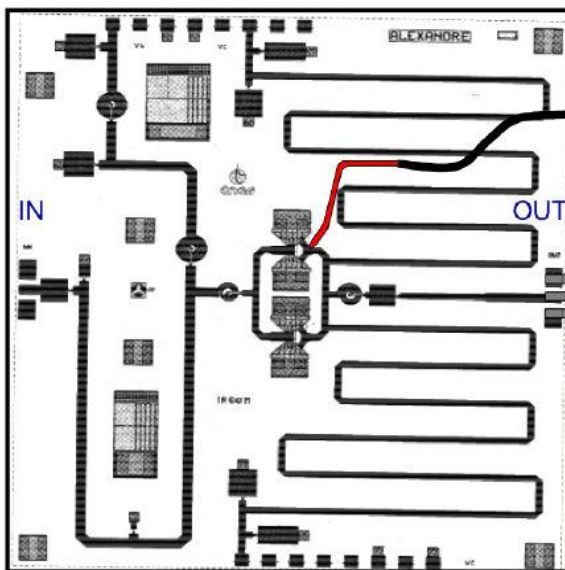


## 3. Define a new error-matrix (NVNA + 2 HIPs)

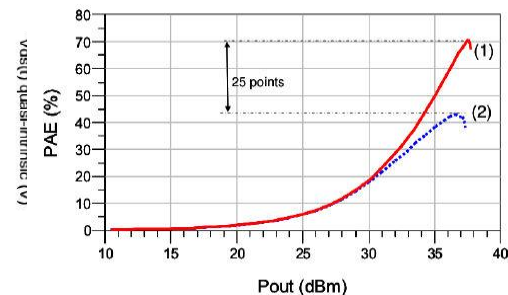
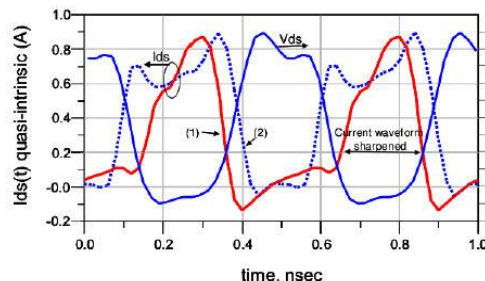
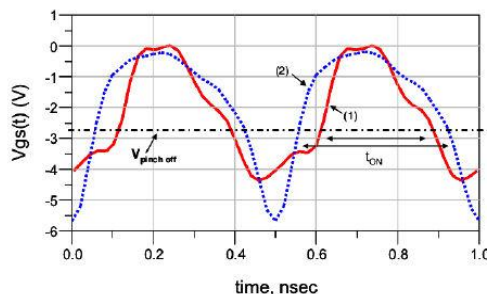
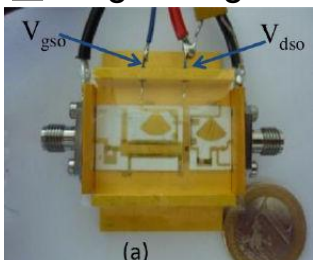
Measurement of 2 voltages

$$\begin{pmatrix} v1 \\ i1 \\ v2 \\ i2 \end{pmatrix} = \begin{pmatrix} \tilde{K}_1 & 0 & 0 & 0 \\ 0 & \tilde{K}_2 & 0 & 0 \\ 0 & 0 & \alpha_2 & \beta_2 \\ 0 & 0 & \gamma_2 & \delta_2 \end{pmatrix} \cdot \begin{pmatrix} r1 \\ r2 \\ r3 \\ r4 \end{pmatrix}$$

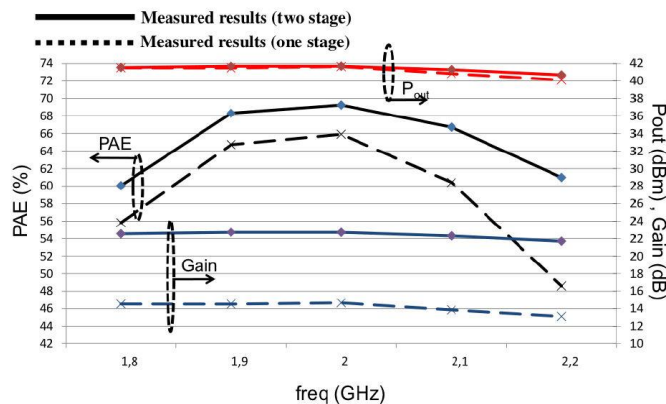
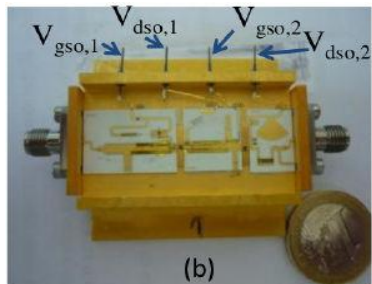
$$\begin{matrix} v1(t) \Leftrightarrow v1(t) \\ i1(t) \Leftrightarrow v2(t) \end{matrix}$$



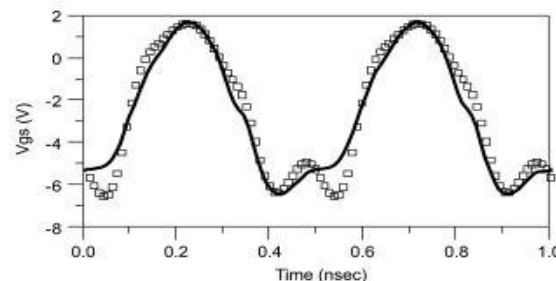
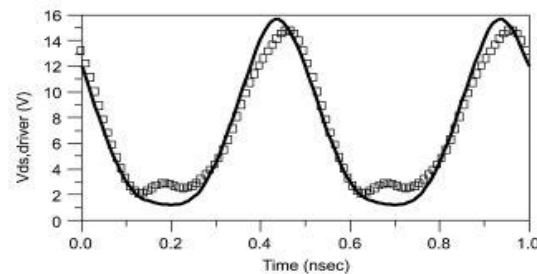
## 1. Single Stage PA with both $f_0$ and $2f_0$ at input: Non-linear model optimized on LSNA measurements



## 2. Using the $2f_0$ from the driver: design of the interstage



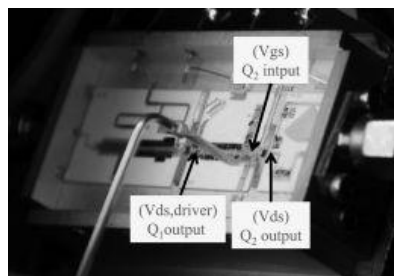
## 3. HIP validation



### A. Ramadan et al.

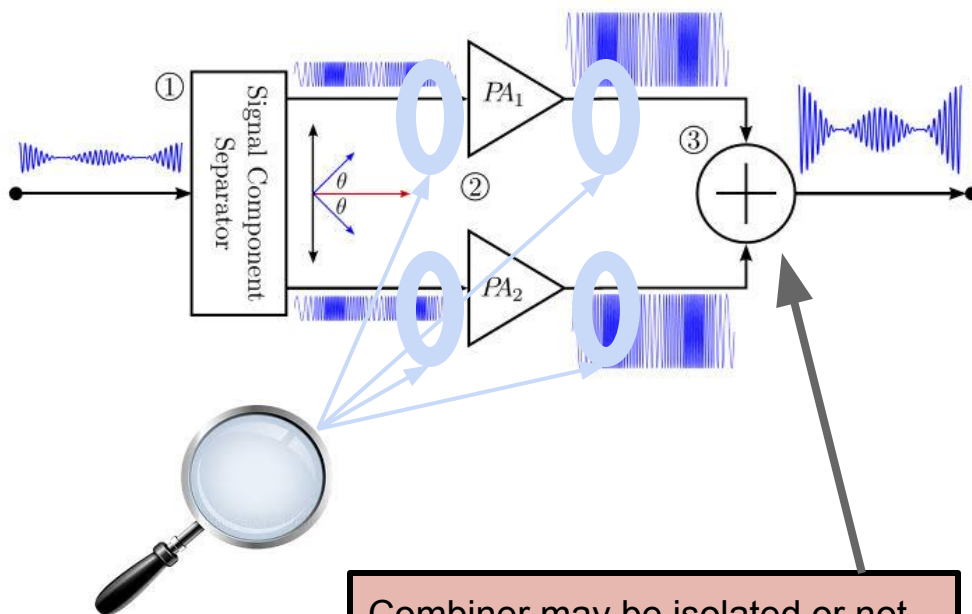
"Two Stage GaN HEMT Amplifier With Gate Source Voltage Shaping for Efficiency Versus Bandwidth Enhancements"  
IEEE Trans. on MTT, Vol. 59, No 3, pp.699 - 706, 2011

[\[Download\]](#)





## Outphasing Principle: Phase modulated constant input power (high PAE)



Combiner may be isolated or not

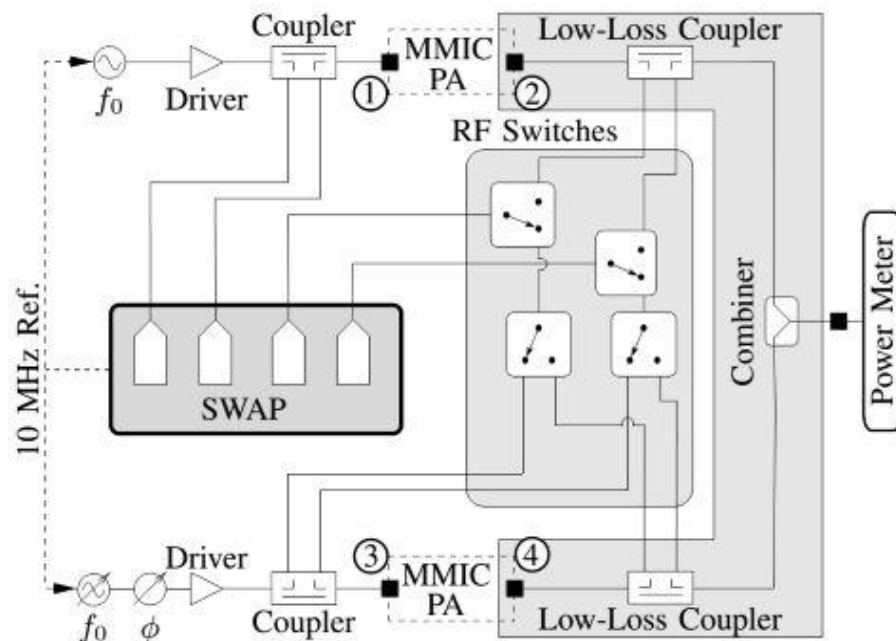
**M. Litchfield et al.**

"X-Band Outphasing Power Amplifier with Internal Load Modulation Measurements"  
EuMW 2014

[\[Download\]](#)

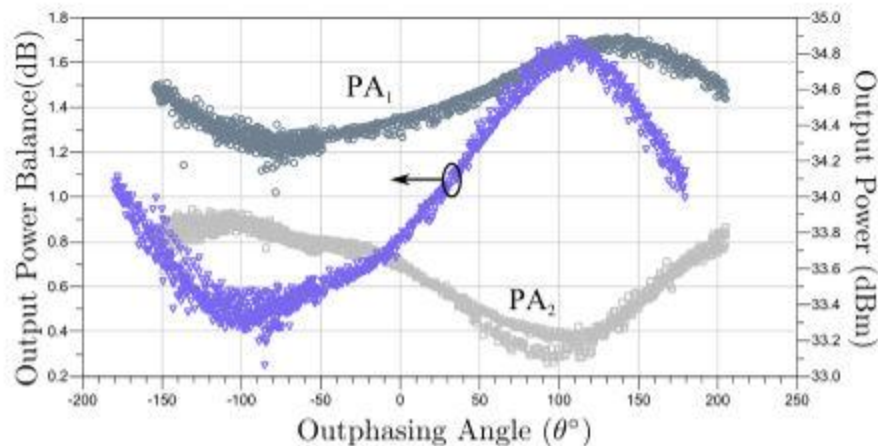
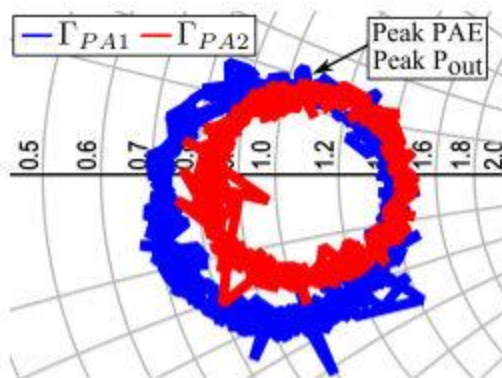
## Dedicated 4-ports LSNA

This method requires the stack of several calibration matrix and a customizable test-set.

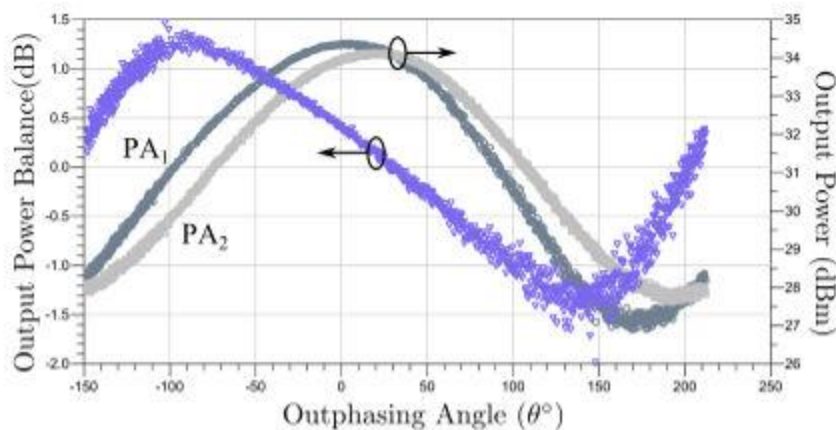
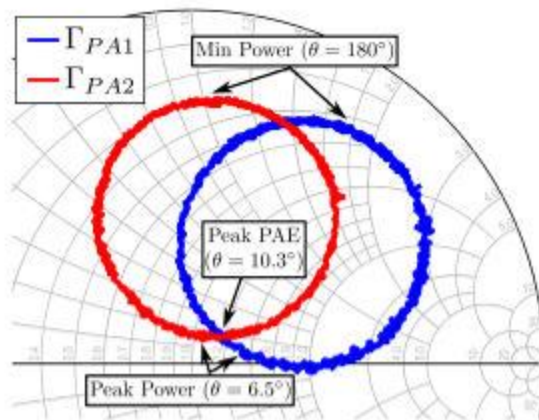


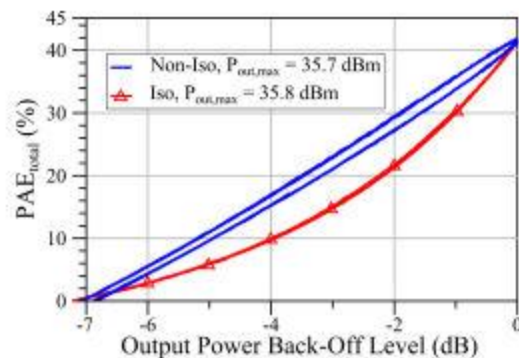


## ISOLATED COMBINER

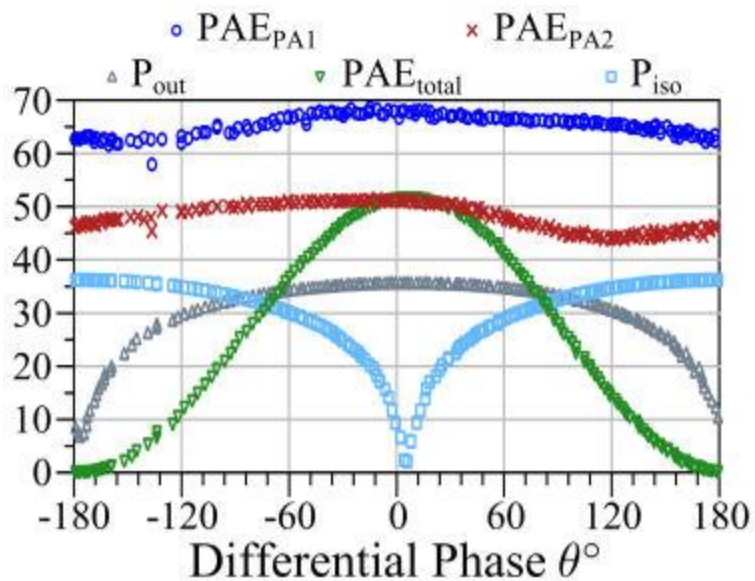


## NON-ISOLATED COMBINER

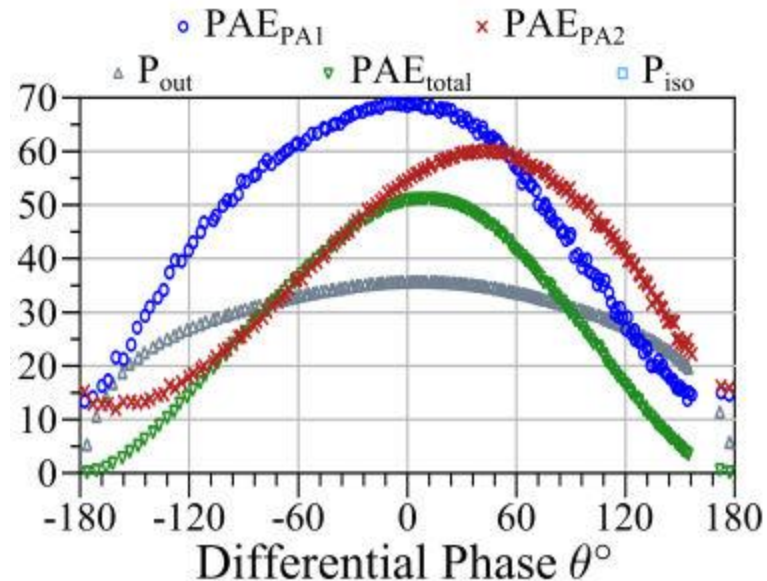




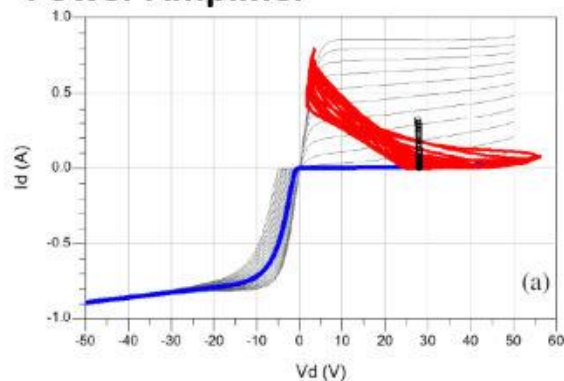
## Isolated Combiner



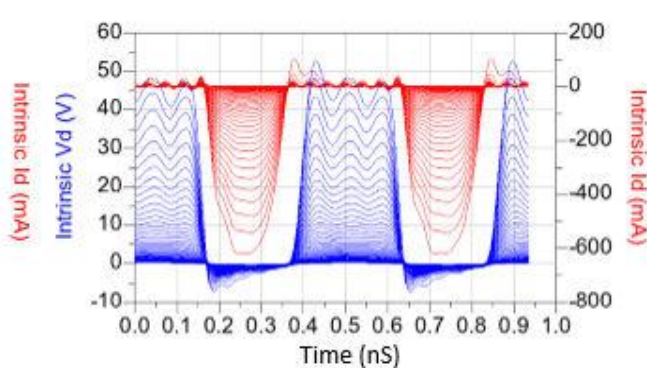
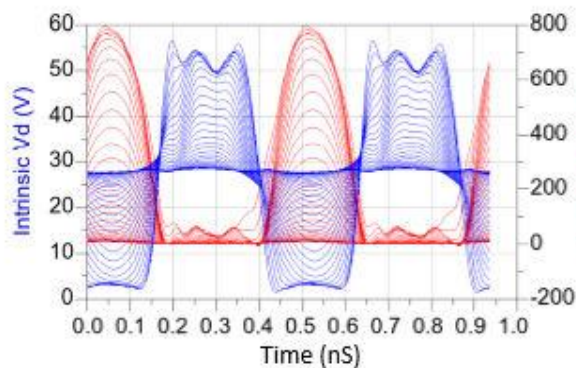
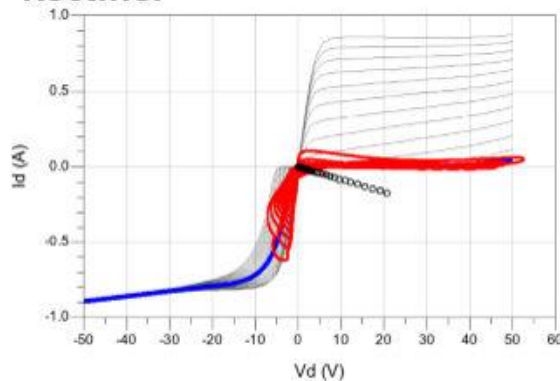
## Non-Isolated Combiner



## Power Amplifier

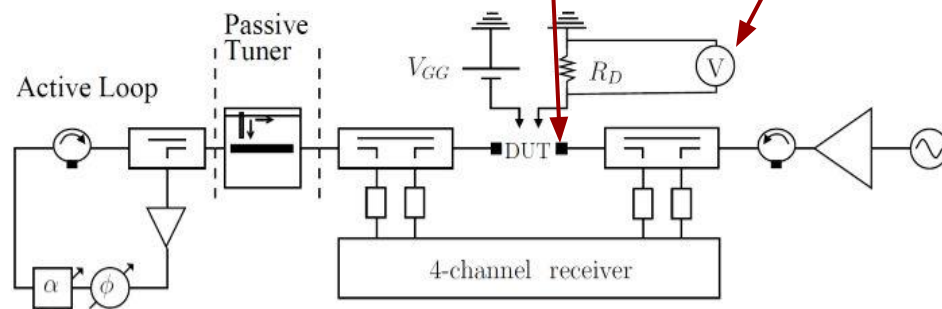


## Rectifier



Simulations at intrinsic current-source

## Setup for Rectifiers



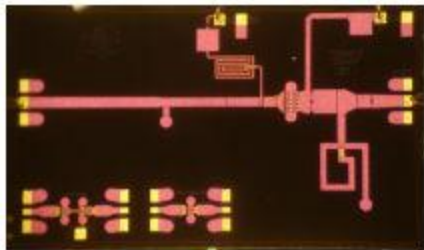
**M. Litchfield et al.**  
 “High-Efficiency X-Band MMIC  
 GaN Power Amplifiers Operating  
 as Rectifiers”  
 IEEE MTT-S, 2014  
[\[Download\]](#)



Unconventional Load-Pull Setup

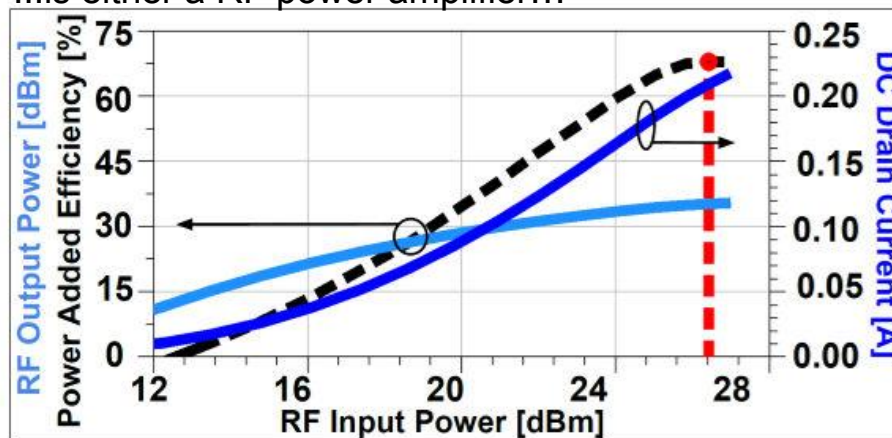


One Circuit...



$f_0 = 10.1$  GHz

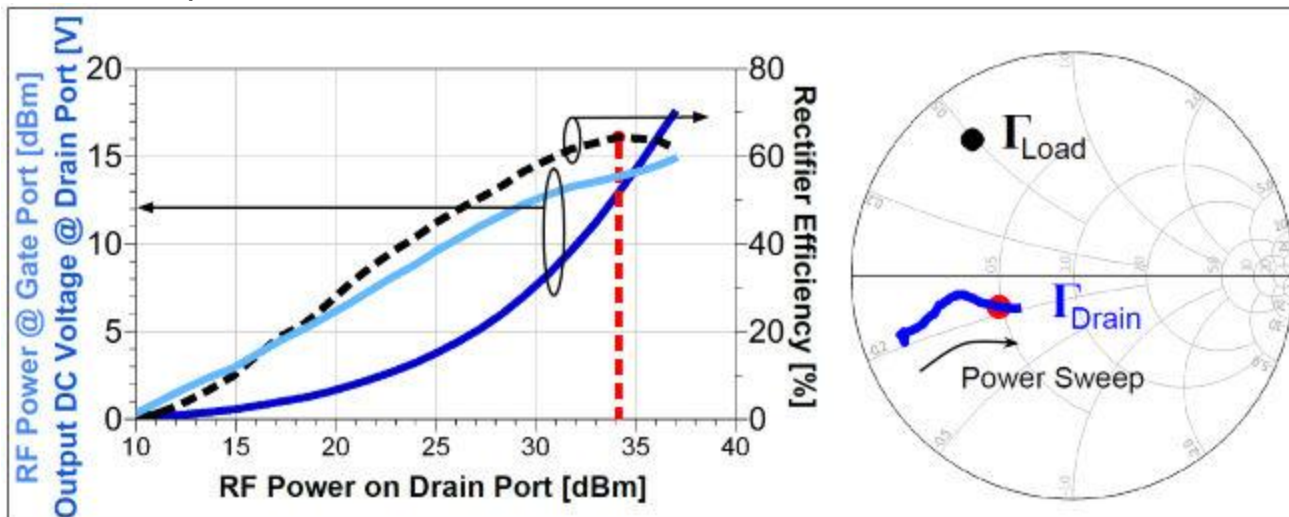
...is either a RF power amplifier...



PAE = 67%  
 Drain Eff = 78%  
 Pin = 26 dBm  
 Pout = 35 dBm

$V_{gg} = -4.0$  V  
 $V_{dd} = 20$  V

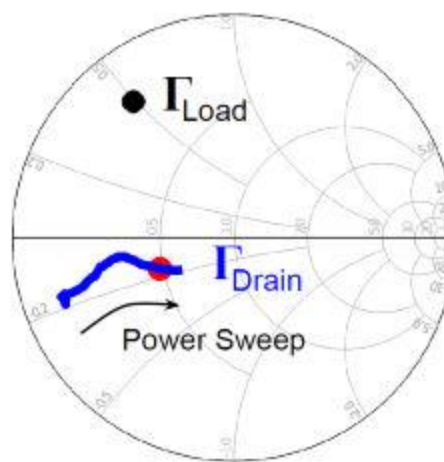
...or a RF power rectifier!



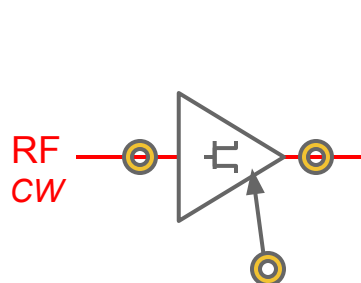
Eff = 64%

$V_{gg} = -4.7$  V  
 $R_D = 100 \Omega$

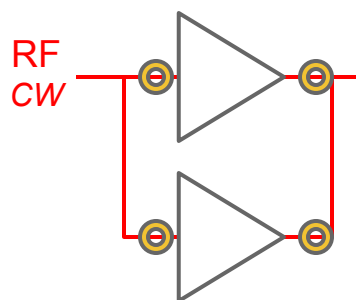
$Z_{load} = 8.45 + j.24.5 \Omega$



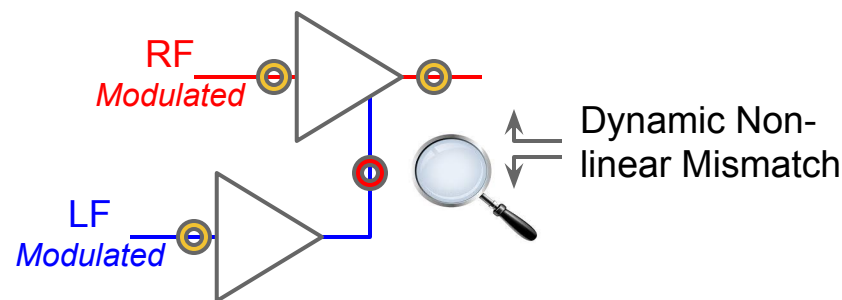




Standard PA



Outphasing  
&  
Doherty



RF PA + Supply Modulator



**Harmonic  
Balance**



**Harmonic  
Balance**



**Envelope  
Transient**

*Simulation  
Tool*

The measurement setup is on progress. It will be presented at the end of this presentation... Thank you for your patience.

**LET'S TALK ABOUT THE LSNA SOFTWARE...**

Setup	Hardware	Software
VNA	VNA	S-parameters AC Simulation
NVNA	VNA	LSSP Simulation X-Parameters
	VSA (4-channels)	Envelope Simulation
LSNA	RF Scope (4-channels)	SPICE Simulation
	Samplers or THAs	Harmonic Balance Envelope Simulation

**SINGLE SHOT ACQUISITION INCLUDING RF HARMONICS**

**COMPRESSED SAMPLING**

A LSNA is basically a software oriented instrumentation.

VNA is a S-Parameter Simulation.

LSNA is an Harmonic Balance Core.

The user has to define a more complicated environment than for a VNA.

LSNA IS NOT A VNA.

**THE CONTROL SOFTWARE CAN NOT BE A  
“CLICK’N GO” INTERFACE.**

## Instrumentation Software

*Standard LSNA (HP / Agilent / Maury)*

*VTD SWAP*

**Commercial LSNA Software**

*Mathematica*

*Embedded*

**User LSNA Software**

*Mathematica*

*Matlab*

*Scilab*

...

*C#*

*Scilab*

...

### **Graphical User Interface is very restricted:**

Good for standard application (multi-harmonic load-pull) ;

Bad for exotic measurements

### **Measurement setups require a dedicated measurement script. Final user needs:**

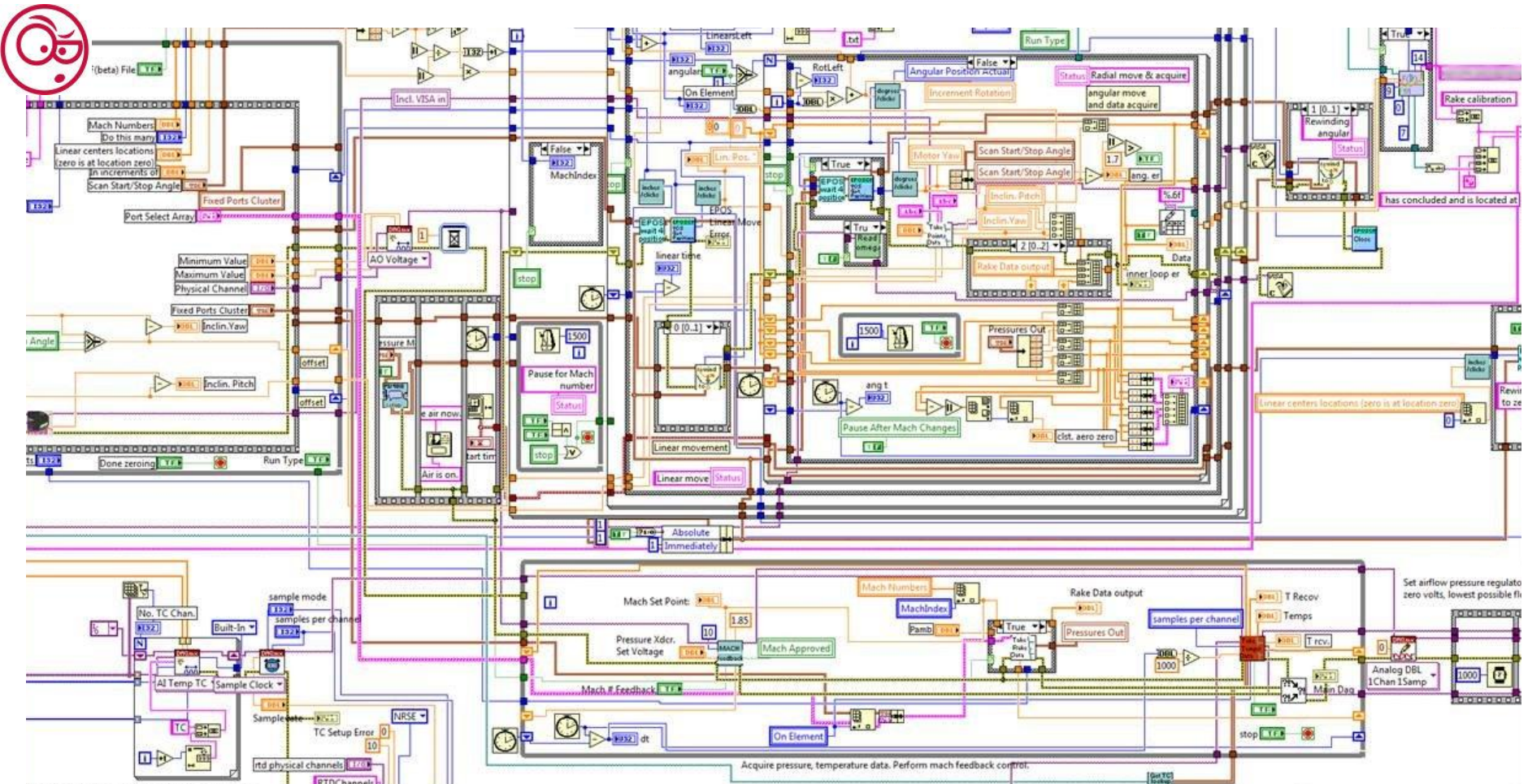
Good knowledge of the software architecture ;

Good knowledge of the development platform ;

## **WHAT ABOUT LabVIEW ?**

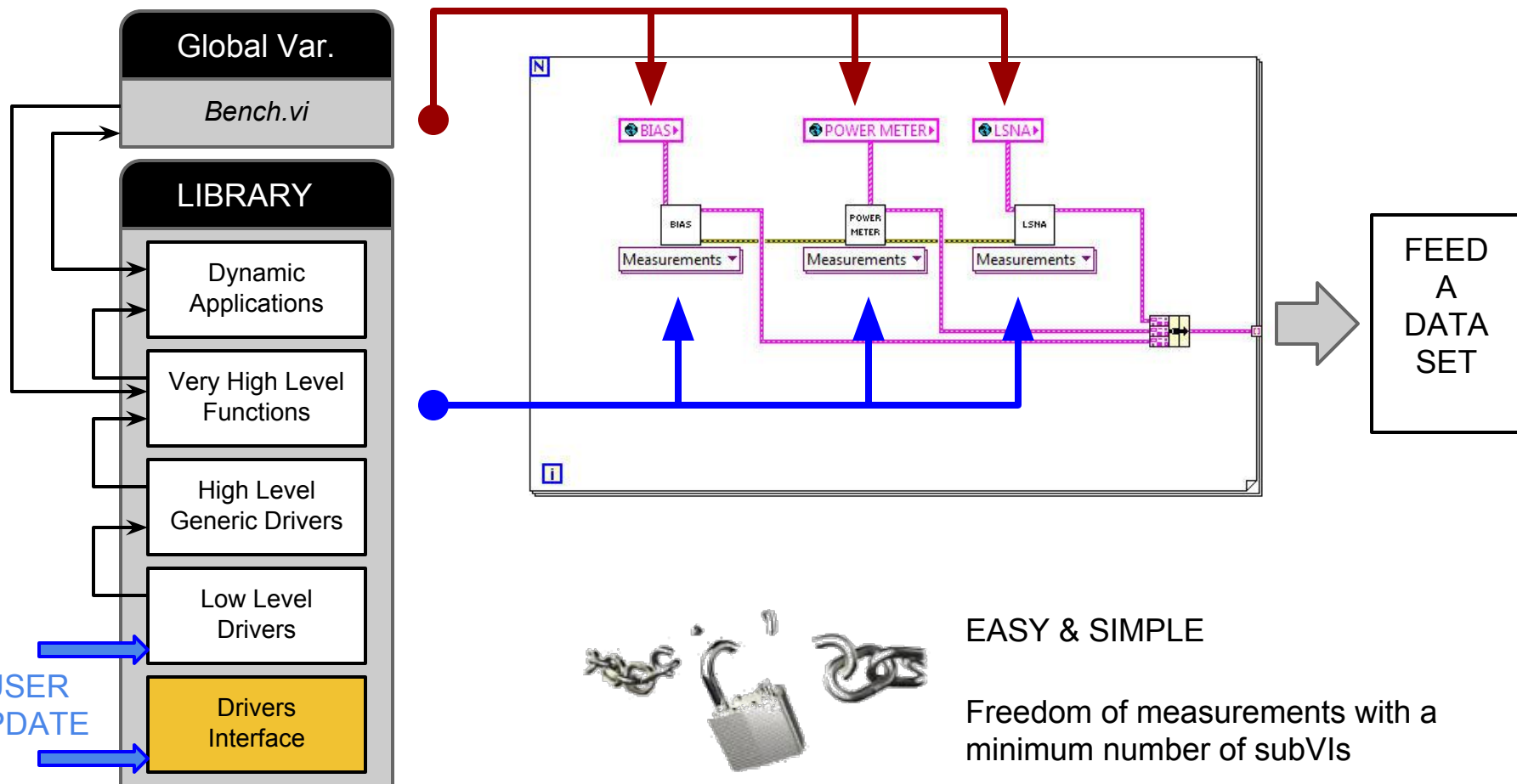


The purpose is to provide a generic LabVIEW library to make this impossible!

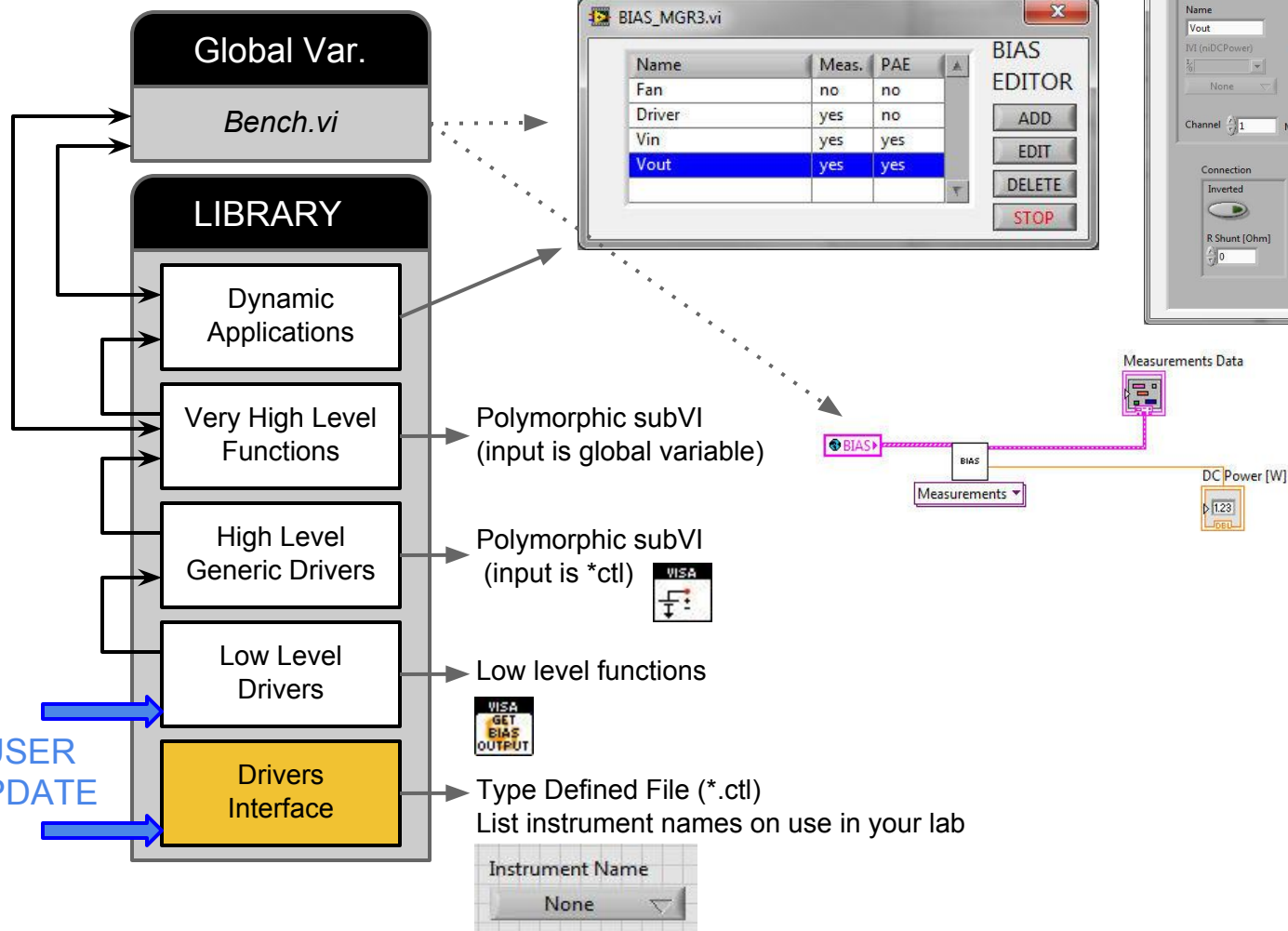


"LabVIEW Spaghetti" coming soon in a Museum of Modern Art

## LabVIEW Open Source Instrumentation Software



## LabVIEW example with BIAS



Measurements Data

Name	V	I
0	0	0

DC Power [W]

0

Output is a cluster of arrays:

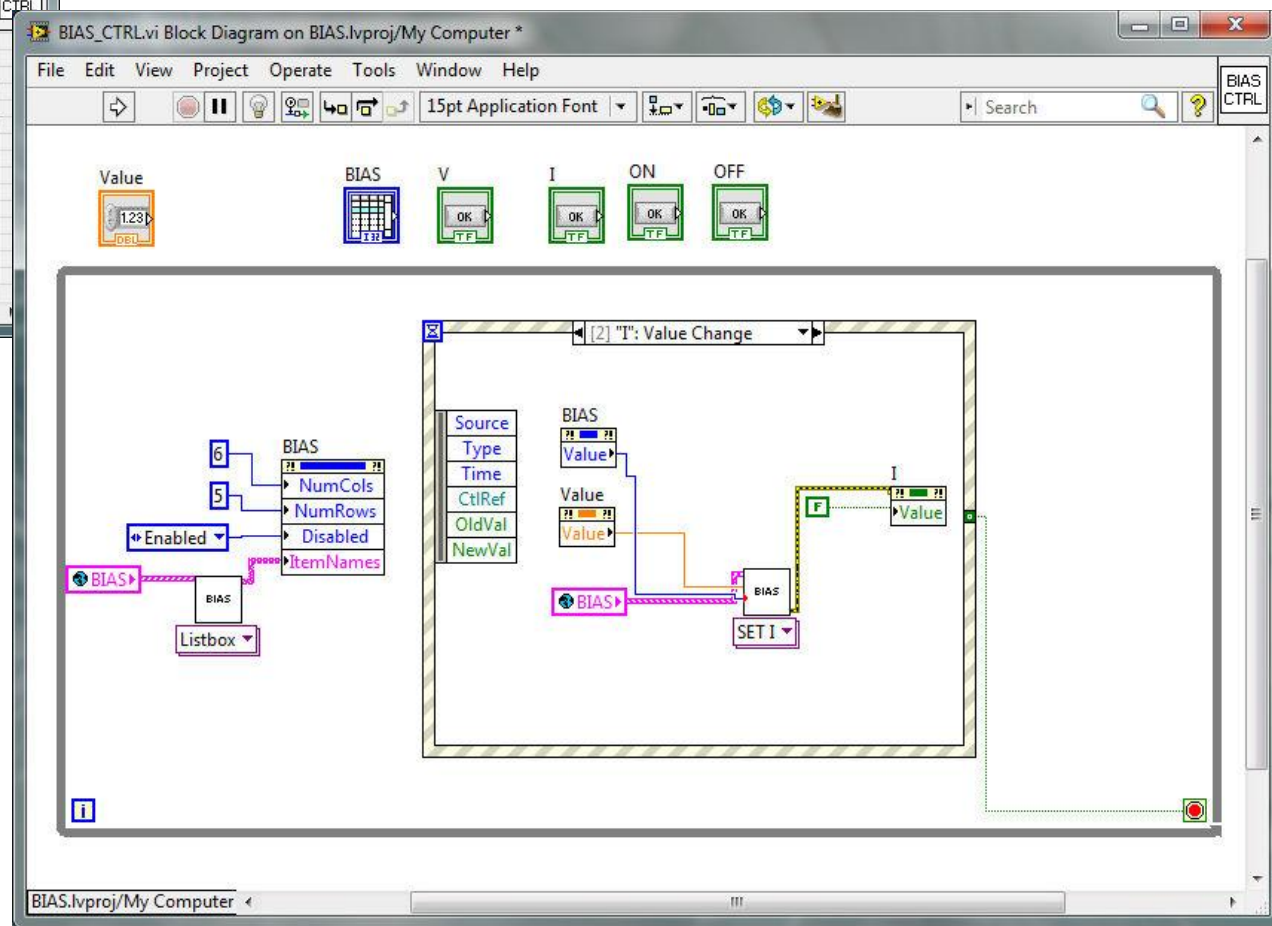
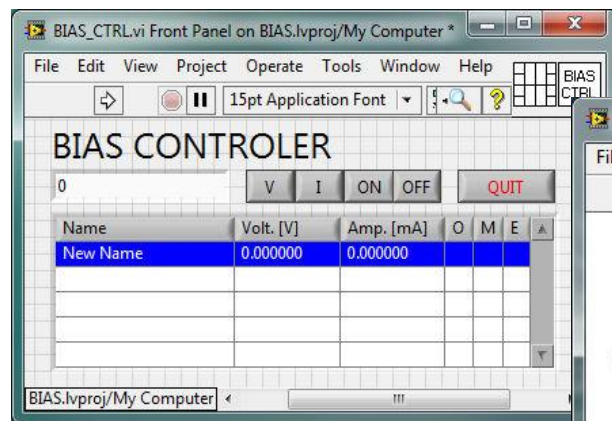
- Name ;
- V ;
- I ;



**DATASET**



## LabVIEW example with BIAS



*Source code ridiculously light  
with this framework*



## Analyzing the dataset

FEED  
A  
DATA  
SET

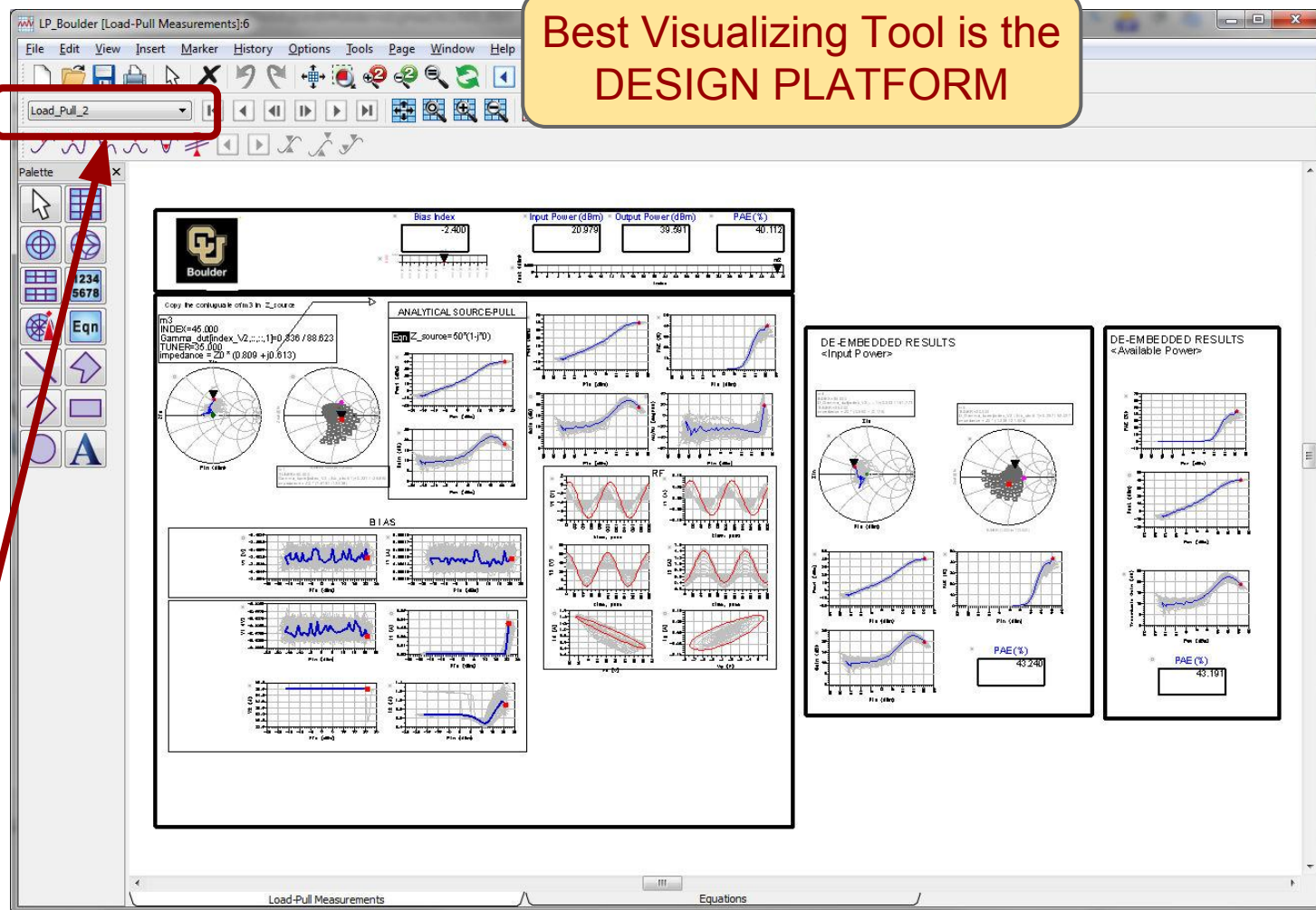
EXPORT DATA in  
**MDIF** or **CITIFILE**

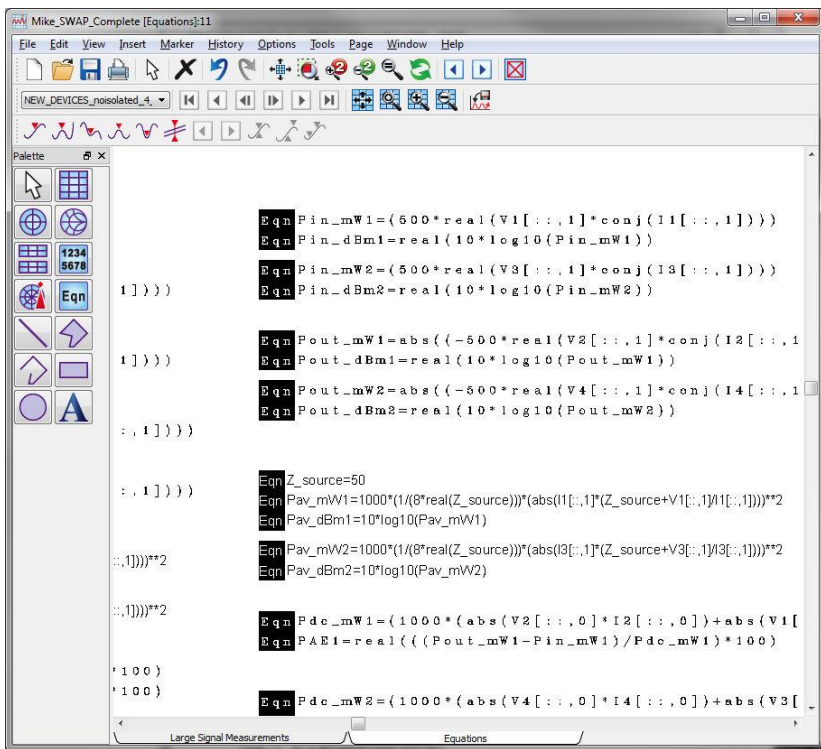
IMPORT in  
DATA DISPLAY tool

Switching datasets  
allow to compare  
easily measurements  
and simulations.

LSNA Load-Pull  
Measurements in  
Keysight ADS

Best Visualizing Tool is the  
DESIGN PLATFORM

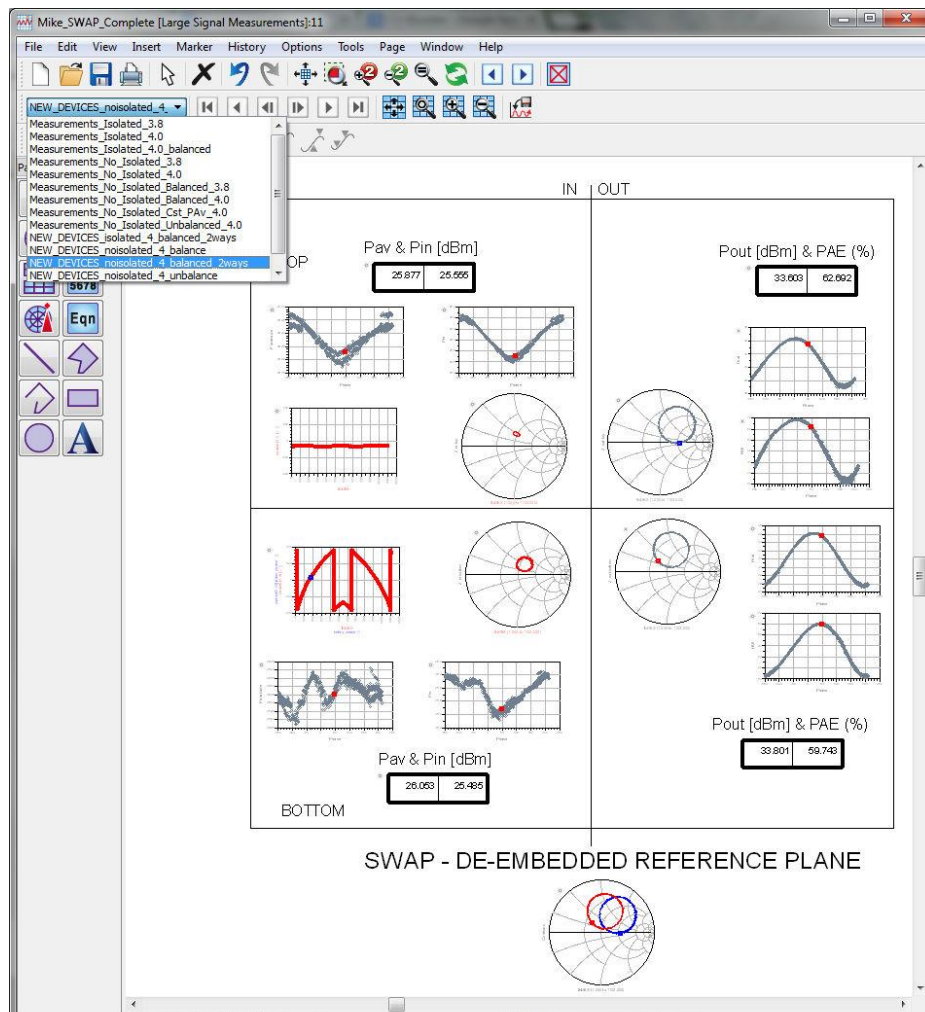




**Only V and I** are recorded at each port.  
 (V and I probes for simulation)

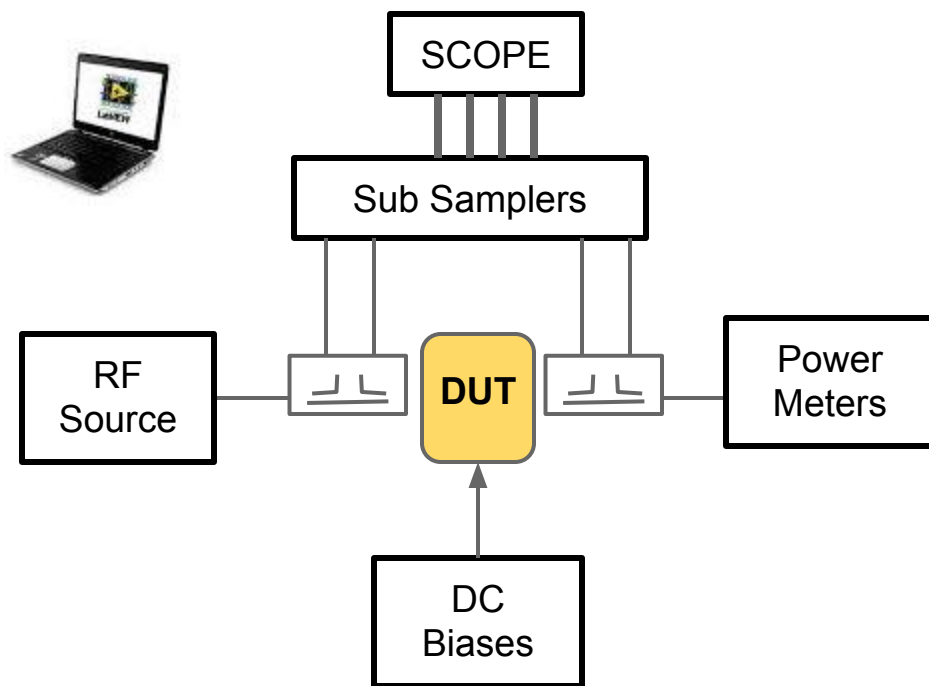
Calculation performed in the datadisplay  
 (i.e. Pin, Pout, PAE, de-embedding...)

Schematic and Data Display templates may change  
 depending of the final application.



*Measurement selection under Keysight ADS  
 for Outphasing Measurements*

## NO LSNA ON THE MARKET?



Most resources are already in your lab... Except the sub-sampler. This element could be a sampler or a Tracking and Hold Amplifier (THA)

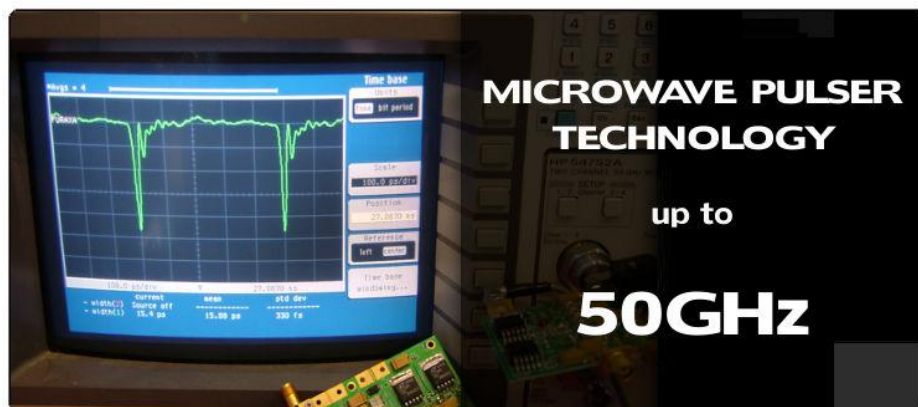
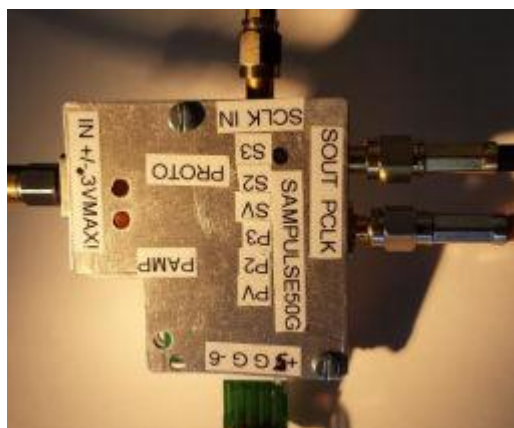
## DO IT YOURSELF!

- No need for a perfect receiver  
*The VNA calibration will take into account the sub-sampler transfer function*
- Good isolation between channels is required  
*Calibration based on the 8-error terms matrix*
- Bi-directional couplers should present an acceptable directivity

### S. Ahmed et al.

"4-Channel, time-domain measurement system using track and hold amplifier for the characterization and linearization of high-power amplifiers"  
International Journal of Microwave and Wireless Technologies, vol.4, no 1, 2012

[\[Download\]](#)


[www.furaxa.com](http://www.furaxa.com)
*InP HBT Sampler IP Core*


## RF Receiver Bandwidth

Maury's LSNA	<b>50 GHz</b>
VTD's SWAP X-402	<b>30 GHz</b>
This sampler	<b>50 GHz</b>

## Clock Frequency

Maury's LSNA	<b>16-20 MHz</b>
VTD's SWAP X-402	<b>600-1200 MHz</b>
This sampler	<b>1-3000 MHz*</b>

(\*) square wave below 200 MHz

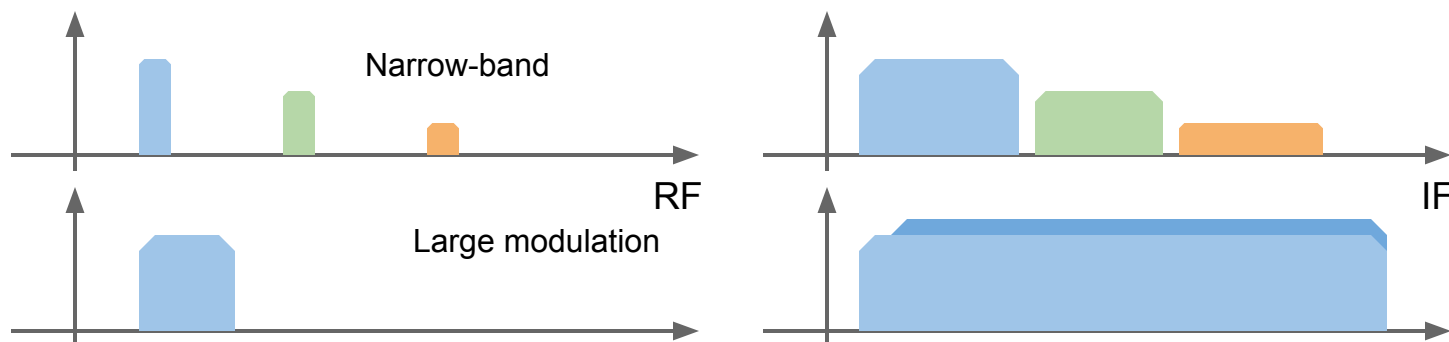
## IF Receiver Bandwidth

Maury's LSNA	<b>20 MHz</b>
VTD's SWAP X-402	<b>100 MHz</b>
This sampler	<b>100 MHz*</b>

(\*) will be updated to 200 MHz



Flexibility on the Clock Sub-sampler frequency enable the complete RF spectrum measurements but Signal Processing necessary to unfold modulated spectrum and retrieve “Envelope Transient” consistent measured data.



Signal reconstruction require a periodic modulation (discrete spectrum).

Two possibilities for reconstruction:

- *Frequency domain*
- *Time domain (unscrambling samples)*

IF bandwidth limit



Complete signal spectrum requires a low sampling frequency (like standard LSNA)

**M. El Yaagoubi et al.**

“Time-Domain Calibrated Measurements of Wideband Multisines Using a Large-Signal Network Analyzer”

IEEE Trans. on MTT, Vol. 56, No 5, 2008

[\[Download\]](#)

## Investigations for Envelope Tracking Applications



**Chassis**  
PXIe-1062Q



**Controller**  
PXIe-8840



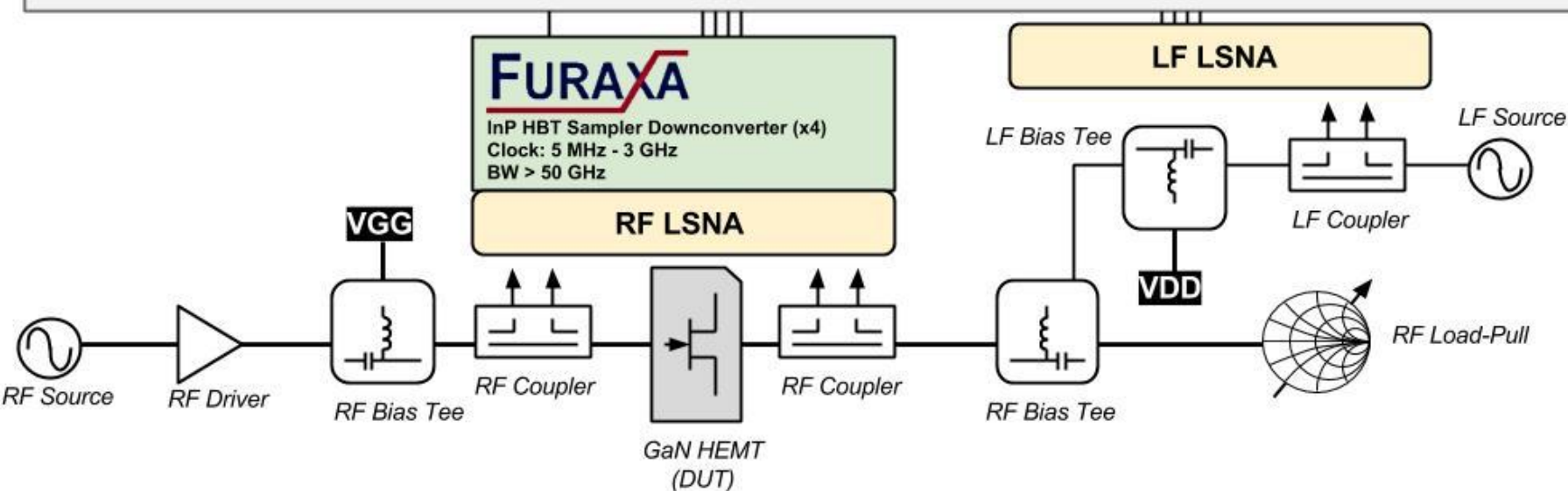
**Sampler Clock**  
PXI-5404



**ADC (4 ch)**  
PXIe-5922 (x2)  
BW=6 MHz (24 bits)



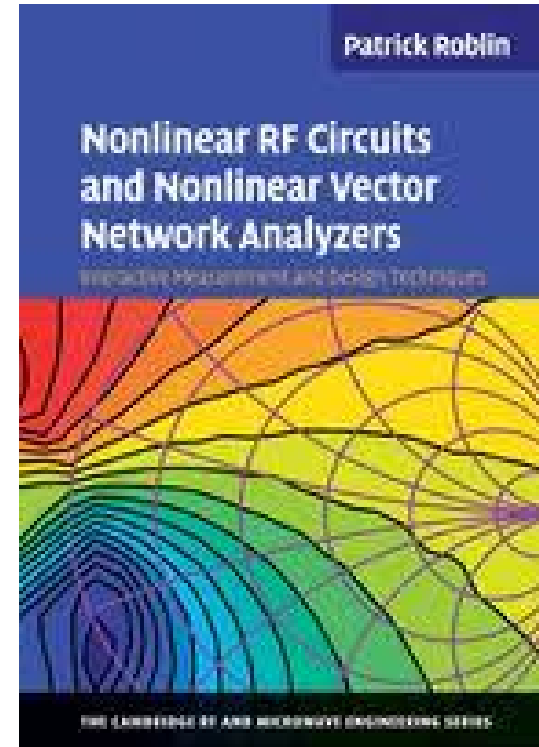
**ADC (4 ch)**  
PXIe-5162  
BW=1.5 GHz (10 bits)



- History of the LSNA from the origins (MTA, 1991) up to now.
- Applications on RF designs
- Current work at CU-Boulder on LSNA software and hardware
- Purpose is to offer a 100% LabVIEW open-source software for user measurement flexibility

This work is funded by National Instruments (Dr. Truchard) through a charitable donation. We would like to acknowledge DARPA (Dr. Greene) and ONR (Dr. Maki) for funding the initial part of this work under grant N00014-11-1-0931

Many thanks to Patrick Roblin for offering the opportunity to present this talk at NVNA users' forum



## **Patrick Roblin**

*Nonlinear RF circuits and nonlinear vector network analyzers: interactive measurement and design techniques*

Cambridge University Press, 2011

*I guess you want a copy of those slides.*

*You can download this presentation right there:*

[www.microwave.fr](http://www.microwave.fr)